An abstract background consisting of a dense, chaotic network of thin green lines. A few lines are highlighted in red and blue. A horizontal line of small yellow dots is visible in the middle of the image.

Summary and Outlook

A nighttime photograph of a street scene. The trees are decorated with warm white string lights. In the background, a building is lit up. People are visible walking on the sidewalk.

Marko Mikuž

University of Ljubljana & Jožef Stefan Institute

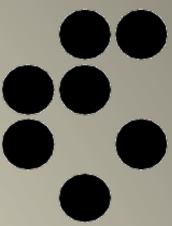
10th Pixel Workshop

Santa Fe, December 16th 2022





Pixel'22 in Brief

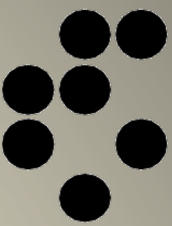


- We've been through 5 exciting (exhausting) days
 - 17 sessions & poster session
 - $20 + 23 + 7 + 21 + 7 = 70 \pm 5$ talks
 - 16 posters
 - Dealing with various aspects of pixel detectors
 - Sometimes loooong pixels called strips
 - Focussing on HEP
 - Operational, in construction, future
 - Not forgetting applications
 - Medicine, space, material science...
- Impossible to pay tribute to every single one...
 - Have to adopt a statistical mechanics approach
 - My sincere apologies to those not mentioned explicitly

Structure of the Talk

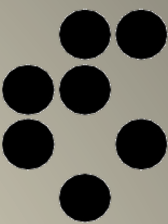
- Pixels started in the 80's
- 1st Pixel Workshop – Genova 2000
- 10th Pixel – Santa Fe 2022
 - There seems to be a natural time constant of 22 ± 2 y
- We enjoy exciting times at the second tick of this clock, the HL-LHC is about to start
- What do we need to do to make
 - 20th Pixel in 2044 (FCC-ee started ?)
 - 30th Pixel in 2066 (FCC-hh about to start ??)as exciting as the 10th ?
- I'll (of course) focus on the latter in my Outlook





Part I : Summary

Historical Prelude



• Pixels from the 80's

CCD Damerell et al.

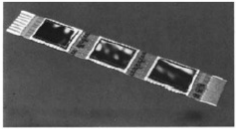


Fig. 1. Photograph of a partly assembled ladder. The 3 upper CCDs have been mounted on the ceramic mother card. The ladder would be completed by mounting 2 further CCDs on the underside, giving continuous coverage over the ladder length of 5 chips.

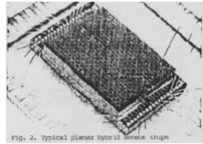


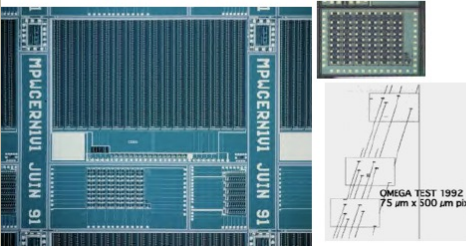
Fig. 2. typical planar layer in silicon chip



Fig. 4. Plot of 300 Ohm/si photo being detected as they traverse a 200 x 200 array illustrating the geometry of two-dimensional readout in aid of pattern recognition.

Gaalema Hybrid SLAC-SSC Shapiro et al.

Hybrid Heijne, Jarron, Campbell ++



OMEGA TEST 1992
75 µm x 500 µm pix

HR-Si Snoeys et al. 1991



Fig. 15. Display of a high energy particle track through the telescope. The negative pulse heights (noise) are not plotted but are of comparable magnitude.

1982 CCD RAL/CERN EP

Chris Damerell & Steve Watts: CCD in NA32 (1985), then SLAC SLD (1989)
-see next slide

1984 IR-MOS Hybrid SLAC/SSC

IEEE-Nucl.Science Symposium, Orlando: Steve Gaalema (Hughes Aircraft) shows hybrid assembly of IR matrix or Ge matrix with bumped CMOS 3T circuit in each pixel with low noise and random-access
40 000 pixels of 50µm

Steve Gaalema. IEEE NS-32(1985) 417-418
S. Shapiro et al., Nucl.Instr.Meth. A275(1989)580-586

1987 Si-CMOS Hybrid/Mono-SOI CERN EF LAA /RD19

Erik Heijne, Pierre Jarron, Michael Campbell full signal processing circuitry support by François Krummenacher, Christian Enz EPFL & Swiss Nat Fund hybrid assembly of Si + 3µm SACMOS, 9x12 pixels, 200µm x 200µm
-see later

1989 Monolithic Hp-Si SLAC/LBL

Sherwood Parker, Walter Snoeys, Chris Kenney 7T circuit in pixel

W. Snoeys et al., Nucl.Instr.Meth. A326(1993)144-140
W. Snoeys et al., IEEE ED-41(1994) 903-911



Silicon Micropattern Detector

tentative characteristics

E. HEIJNE LONDON Conf. 1987

- 2-dimensional array of detecting elements
just 35 years ago

- granularity of 20-100 µm

- no insensitive regions between segments

- in situ signal processing, giving digital output
zero suppression, local ADC

BINARY OR DIGITAL

- memory function until external trigger/clear

- hierarchical information structure using mosaic of devices

- recognition of useful data (patterns)

- active area per device > 100 mm²

$$1\text{m}^2 = 10^4 \text{ devices}$$

- boundary conditions in:

$$\text{power dissipation} < .1 \text{ W/cm}^2$$

$$\text{radiation tolerance } 10^7 \text{ rad}$$

$$10^{14} \text{ neutrons}$$

A DREAM ?

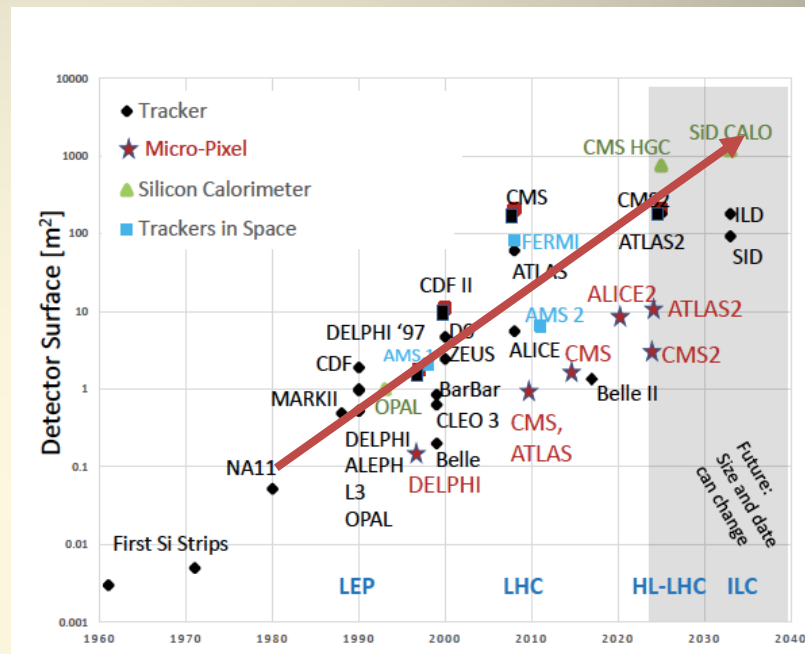
NIM A 273 (1988) 615

• Wishlist in 1987

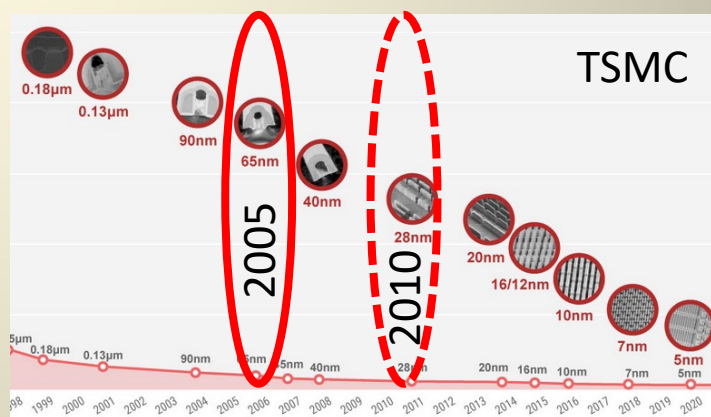
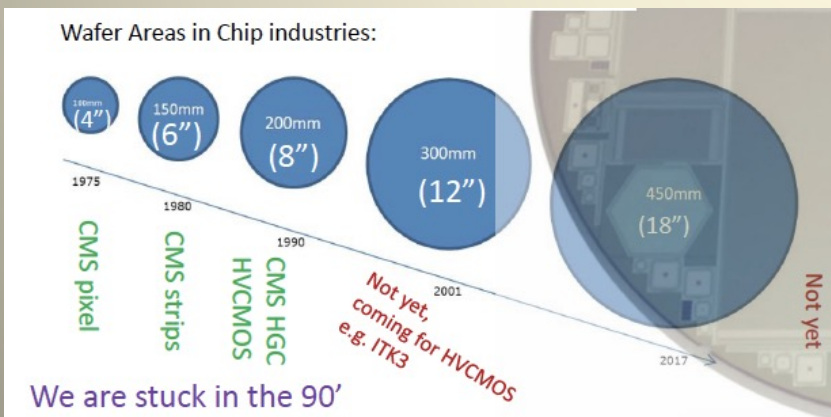
E. Heijne

Dreams Come True

- Position sensitive silicon detectors in HEP
 - Moore's law
 - Doubling in 4 years
 - For strips and pixels
- Not exactly technology drivers
 - Just made it to the '90s in sensor wafers
 - In 2005 for CMOS (->2010)

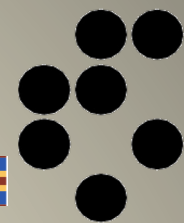


Log-scale



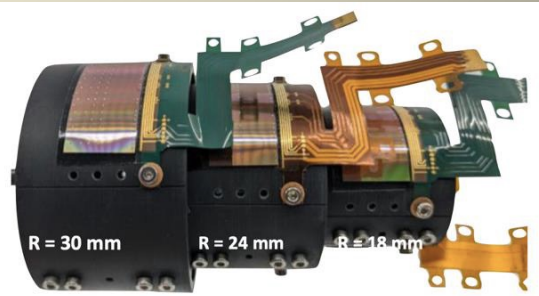
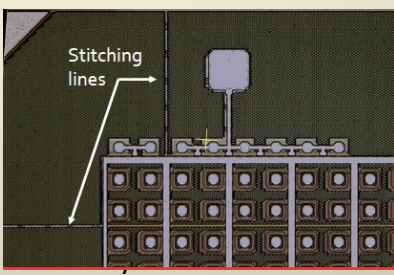
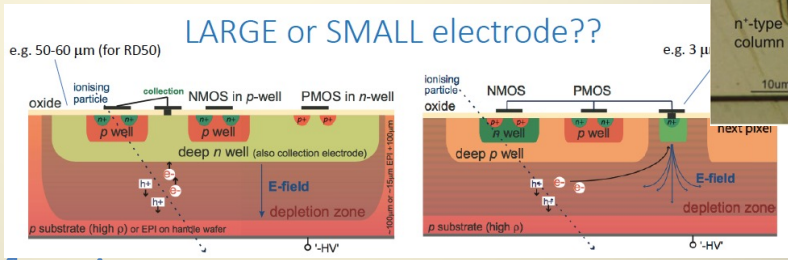
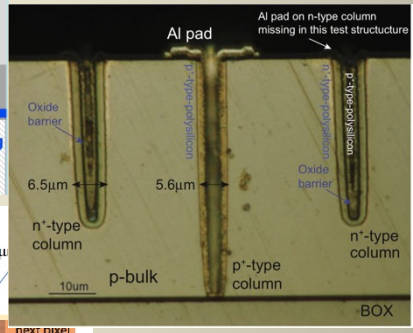
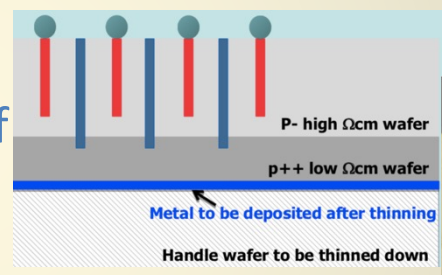
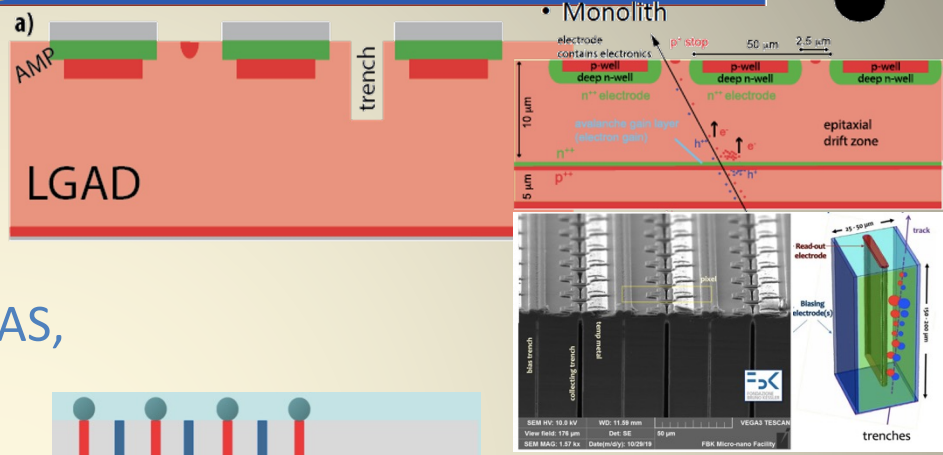
F. Hartmann

Beyond the Dream



F. Hartmann

- 4-D tracking
 - 4th D: timing (<50 ps)
 - LGAD's, trench (@column ?) 3-D...
 - In fact 5-D: energy
 - Timing layers (LGAD) in Phase2 (ATLAS, CMS)
- 3-D sensors have made it !
 - From ATLAS IBL to inner pixel layers of Phase2 in ATLAS & CMS
 - Yield under control (done deal ?)
- From hybrid to monolithic
 - The future of tracking
 - (Too?) Many approaches
 - No application in Phase2
 - Reticle stitching allow wafer size detectors
 - Thinning allows bending (ITS3)
 - Run5 upgrades are theirs !



Current Pixel Systems

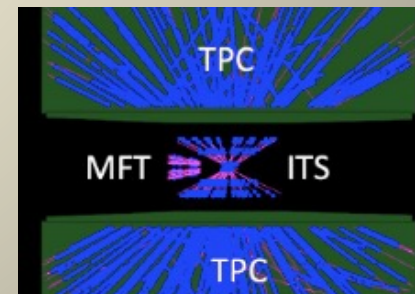
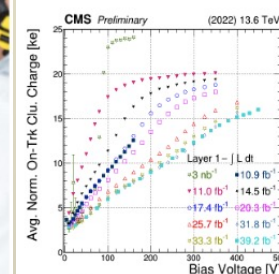
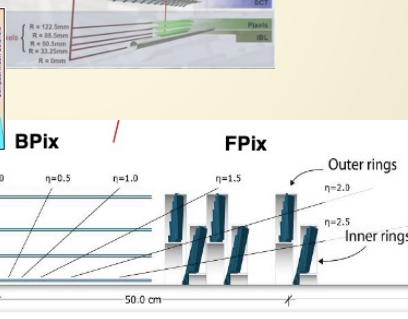
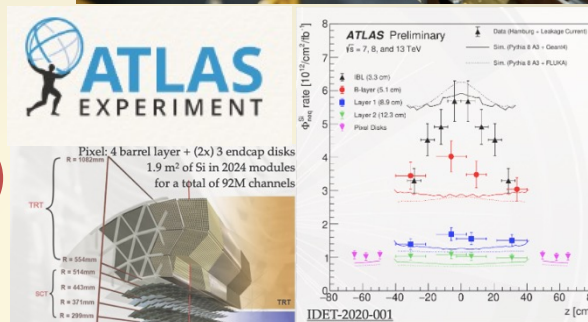
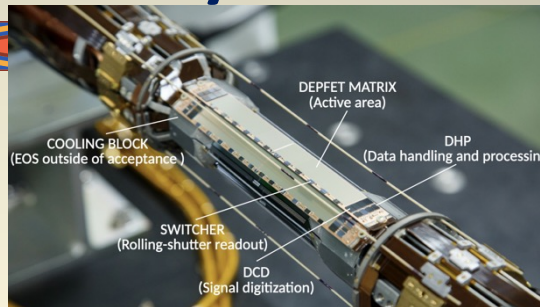
- Belle II, ATLAS, CMS, ALICE

- Wildly different requirements and realizations

- DEPFET (incomplete, 2023)
- 3D, planar hybrid (LS0, LS1)
- Planar hybrid (LS1, LS2)
- MAPS (LS2)

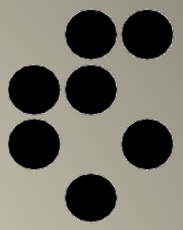
- Common

- They all perform !

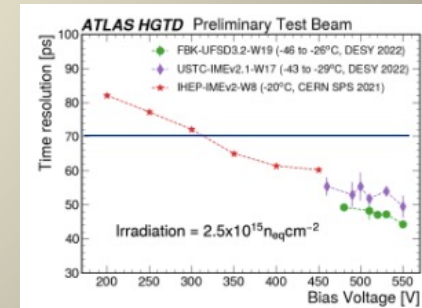
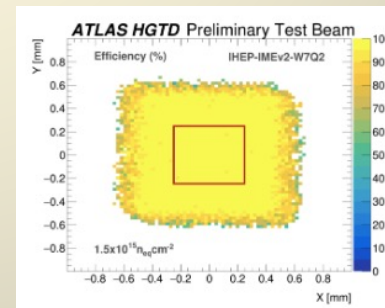
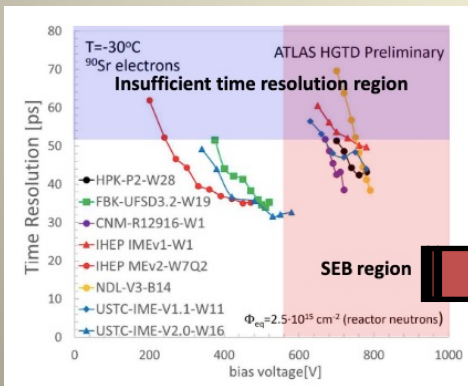
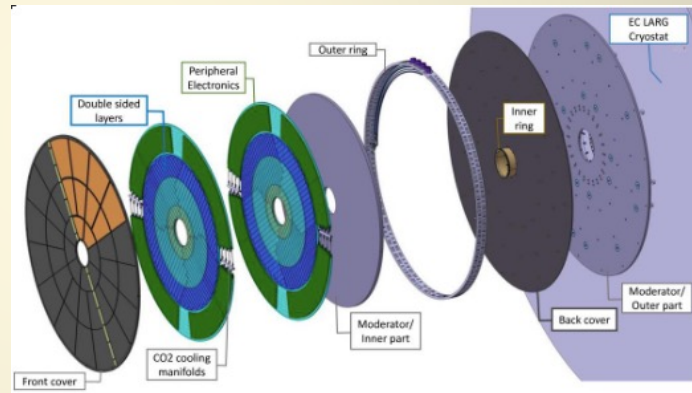
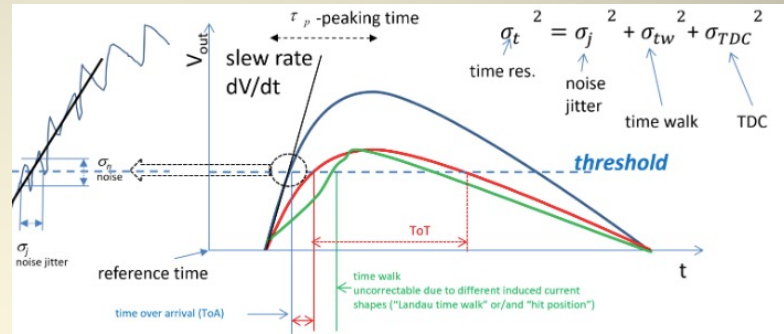




Precision timing



- Goal <50(30)ps
 - Ultimate: 5ps FCC-hh
- Progress on all contributions
 - Sensor and electronics
- 50 ps timing resolution achieved on large scale
 - ATLAS HGTD
 - C-enriched LGAD
 - up to $2.5 \times 10^{15} n_{eq}/cm^2$



Precision timing (cont.)

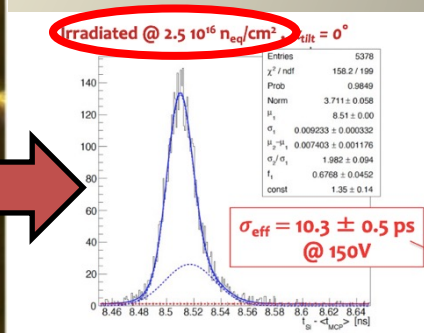
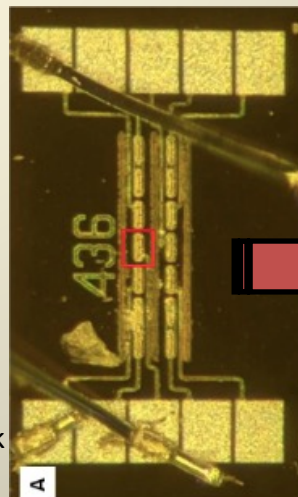
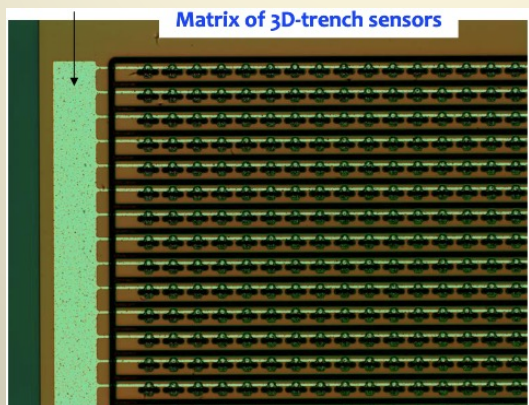
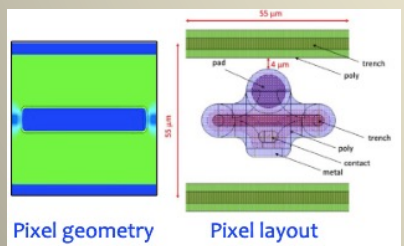
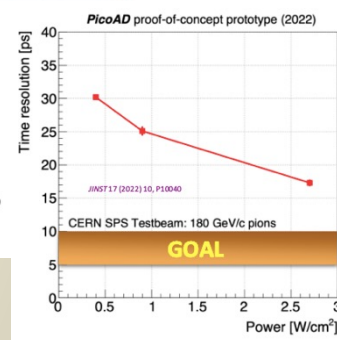
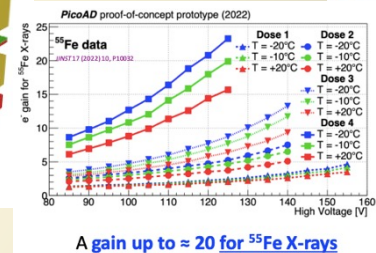
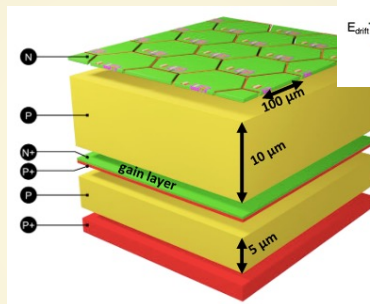
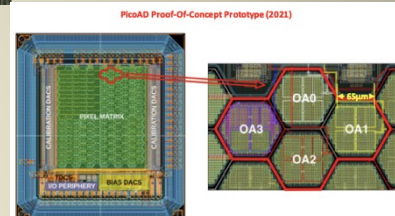
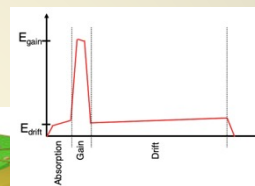
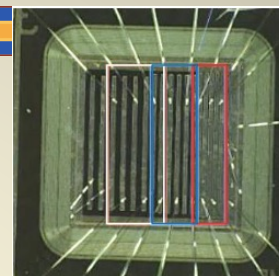
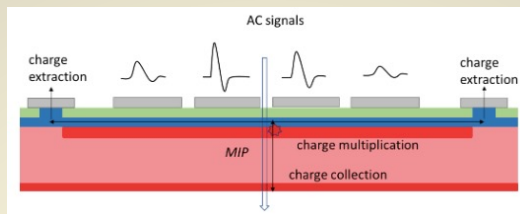
- LGAD flavours

- AC-LGAD

- true 4-D -> ATAR, EPIC



- 3D trench



Space, Astronomy, Dark Matter

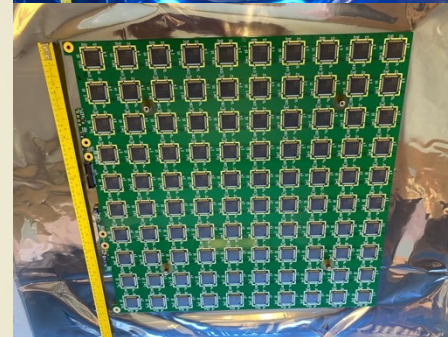
- Neutrinos - LArPix
 - LAr TPC
 - Cryo, huge



DUNE
(1/200)
LAr
87K



1000 m²
DUNE near

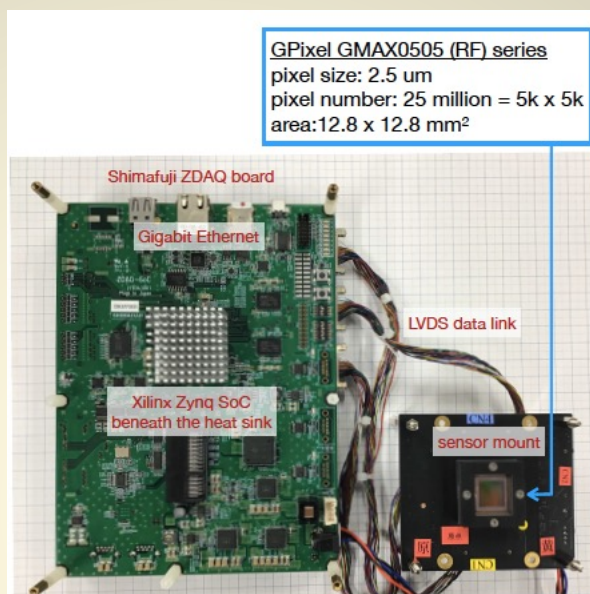


- Gamma rays
 - Adaptation of ATLASPix for space
 - HEP → astronomy
 - AstroPix v1, 2, 3
 - AMEGO-X mission

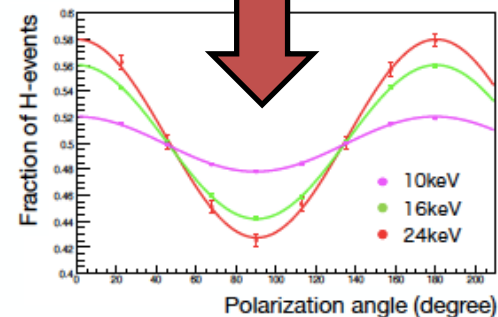
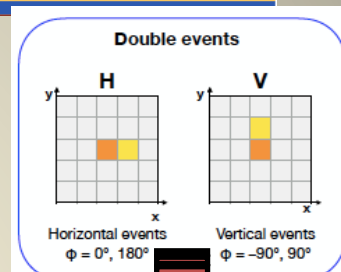


Space, Astronomy (cont.)

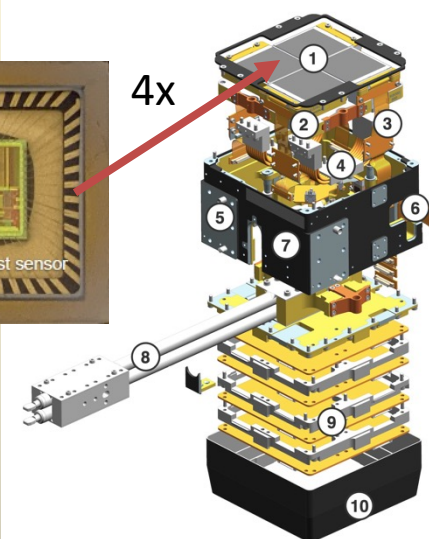
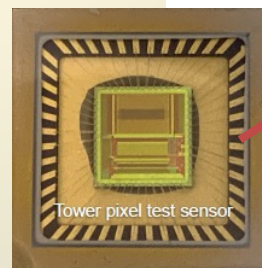
- X-ray polarimeter
 - GigaPixel
 - 5k x 5k pixels
 - Up to 15 % modulation



GPixel GMAX0505 (RF) series
 pixel size: 2.5 μm
 pixel number: 25 million = 5k x 5k
 area: 12.8 x 12.8 mm^2



- UV-astronomy
 - Tower 180nm MAPS stiched to 4.5x4.5 cm^2 active area
 - 4 MAPS -> 90Mpixel camera
 - Ready for launch in 2025



- 1 Sensors
- 2 Mosaic assembly
- 3 Rigid-flex sensor cable
- 4 Thermal straps
- 5 Spider interface
- 6 Cable towards satellite
- 7 Frame
- 8 Heat pipe system
- 9 Power supply boards
- 10 Housing

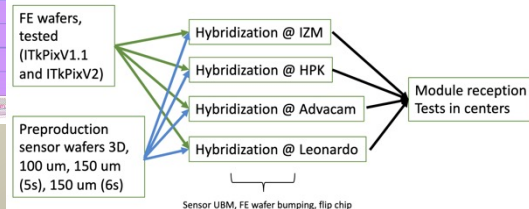
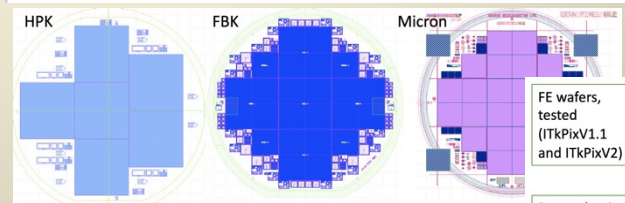
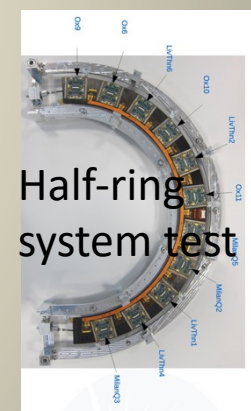
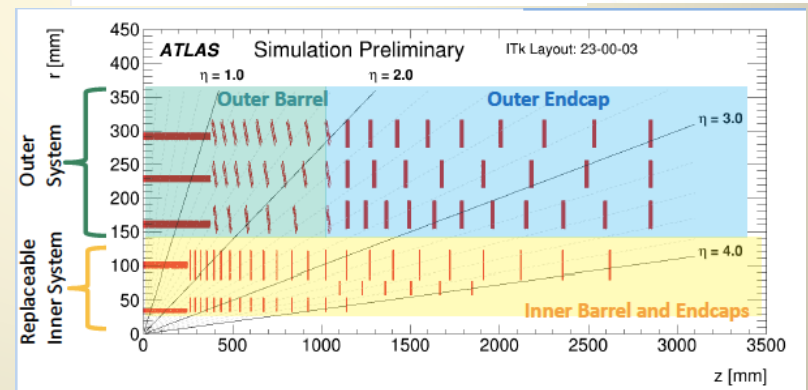
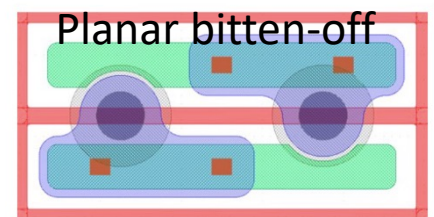
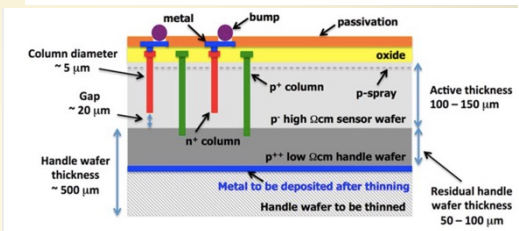
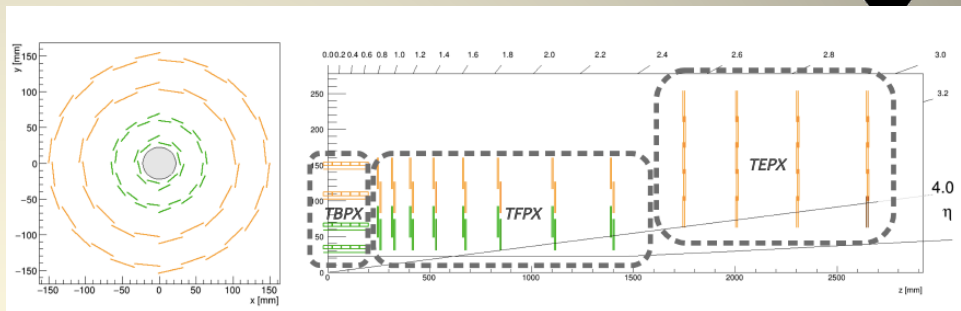
Pixel System Upgrades – Run4

- CMS Phase II

- 4.9 m², 3900 modules
- 3D inner layer, 150 μm
 - thermal constraint
- The rest 150 μm planar
- All cells 25x100 μm²

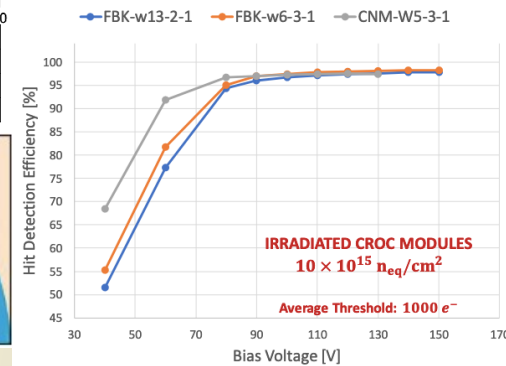
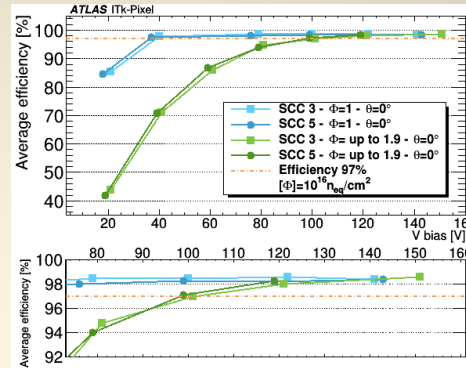
- ATLAS ITk Phase II

- 13 m², 9400 modules
- 3D layer L0, 150 μm
- The rest 150 μm planar
 - 100 μm in L1
- Cells 50x50 μm²
 - Except 3D L0 25x100 μm²

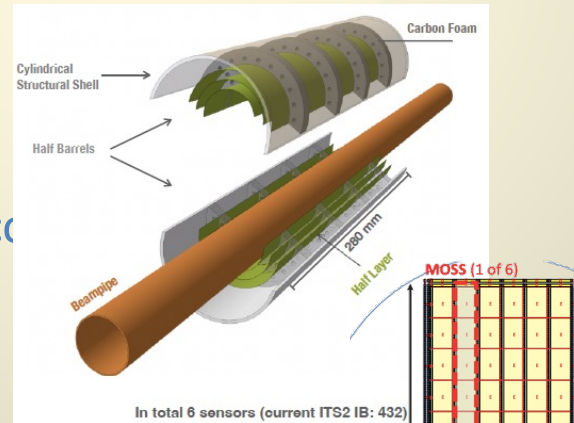


Pixel System Upgrades (cont.)

- ATLAS & CMS 3D modules
 - FBK 3D sensors
 - ITkPixV1.1 or CROC
 - Irradiated to $1\text{-}2 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$
 - Need 90-120 V for \sim full efficiency
 - Comfortable operation window before (soft) breakdown



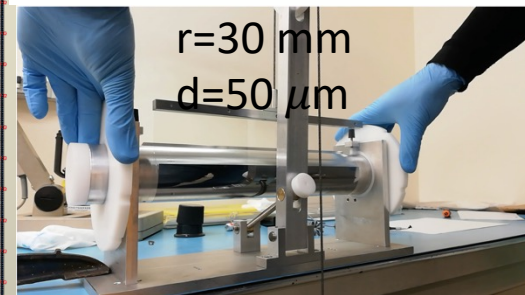
- ALICE ITS3
 - 3-layer cylindrical
 - $50 \mu\text{m}$ thick Si
 - self-supporting, air $0.05\% X_0$
 - MAPS in 65 nm
 - Wafer-scale stitching



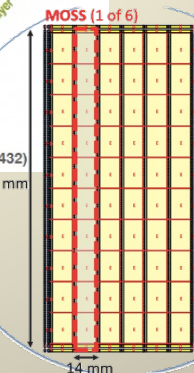
ITS3, Even closer, thinner, better:

- 18 mm from IP
- **<0.05% x/X_0 per layer, Inner Barrel**
- pixel size $\sim O(20 \times 20) \mu\text{m}^2$

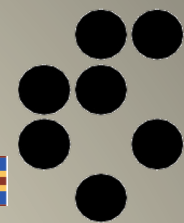
→ Replace 3 innermost layers with wafer-size, truly cylindrical layers



- MOnolithic Stitched Sensor - MOSS



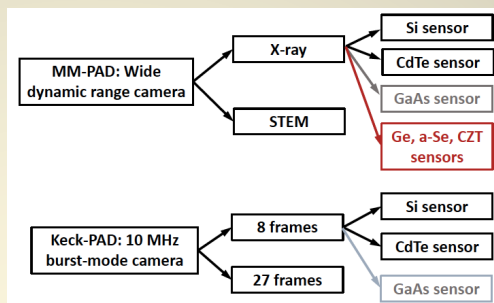
X-ray Detectors



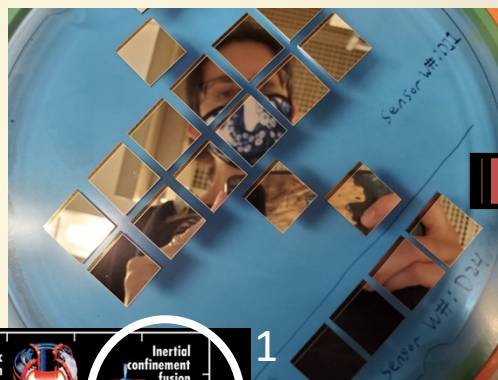
- Cornell

- MM-PAD 1.0 and 2.1

- Integrating
 - Dynamic range extension by overflow counting
 - Hybrid: Si, CdTe

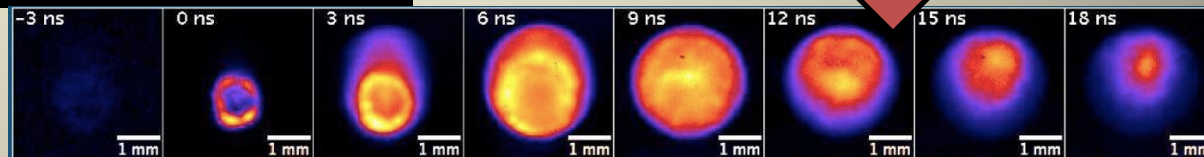
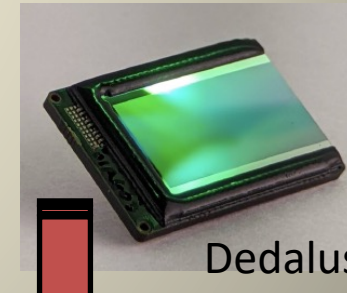
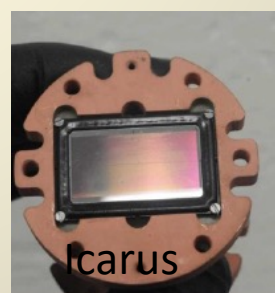
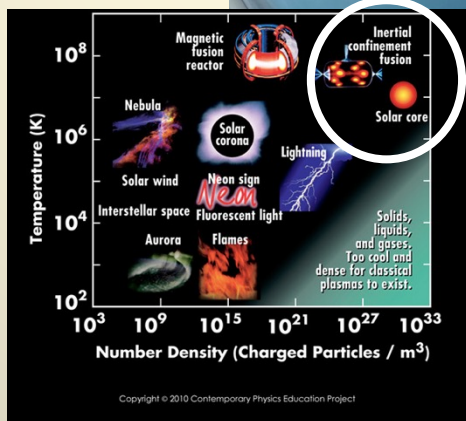


Specification	MM-PAD-1.0 (8 keV equivalent units)	MM-PAD-2.1 target (20 keV equivalent units)
# of pixels per chip	128 x 128	128 x 128
Pixel size	150 μm	150 μm
Sensor	Si	CdTe
Electron-collection capability?	No – holes only	Yes – collect electrons or holes
Frame rate	1.1 kHz	≥1.1 kHz
Duty cycle	0% at max frame rate	≥ 90%
Read noise	0.16 photon	≤ 0.1 photon
Well capacity	4.7x10 ⁷ photons	10 ⁸ photons
Instantaneous photon rate	> 10 ¹² ph/s/pix	> 10 ¹² ph/s/pix
Sustained photon rate	> 10 ⁸ ph/s/pix	> 10 ² ph/s/pix

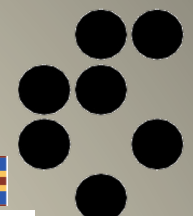


- Ultra-fast

- X-ray “movies”
 - HDEP e.g. ICF
 - Icarus, Dedalus
 - Hybrid
 - ns shutters

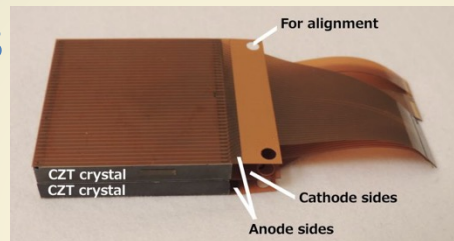
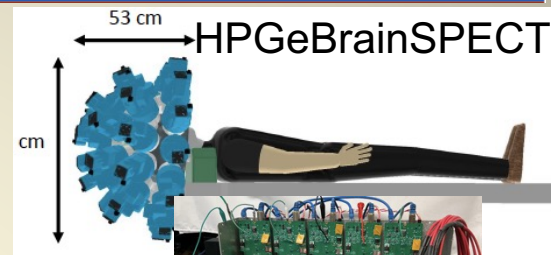
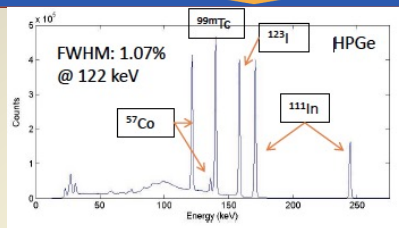


Imaging (Medical, IR, DE)



- Ge and CZT hybrid for SPECT/PET

- DSSD
- Scaled up assemblies



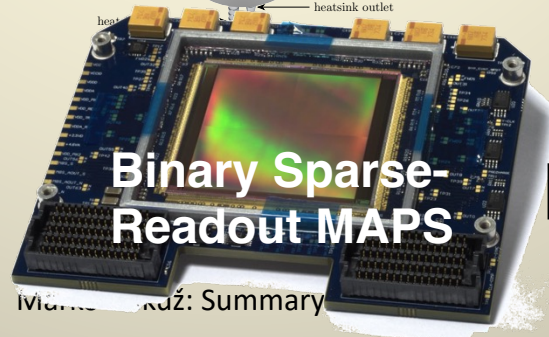
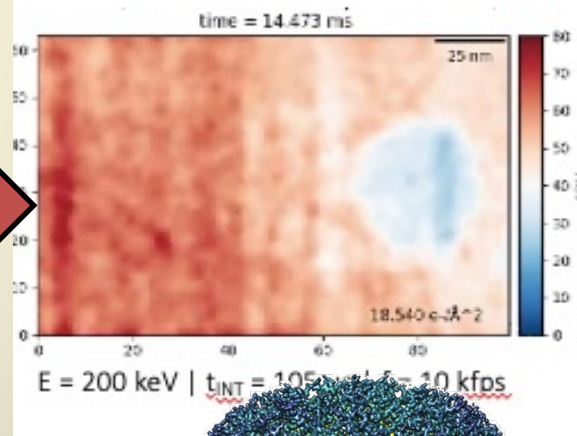
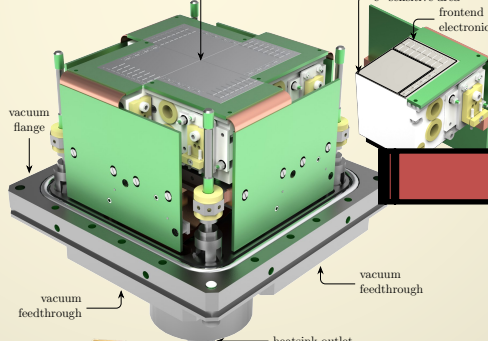
x 110



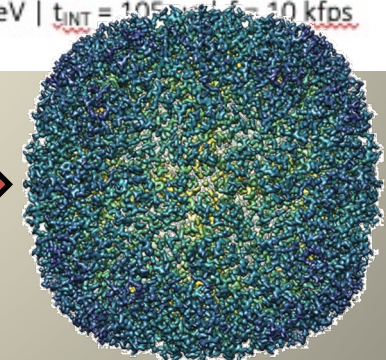
- DEPFET/MAPS monolithic for direct electron at SEM

- Fast, precise and large
 - TEM movies (DEPFET)
 - sparsification and electron counting (MAPS)

MPI HILL FEDT DH80k

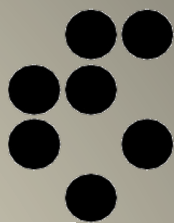


→

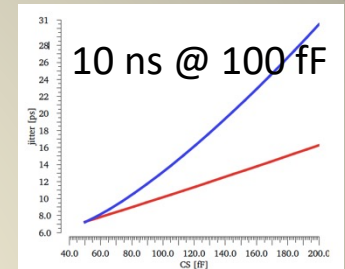




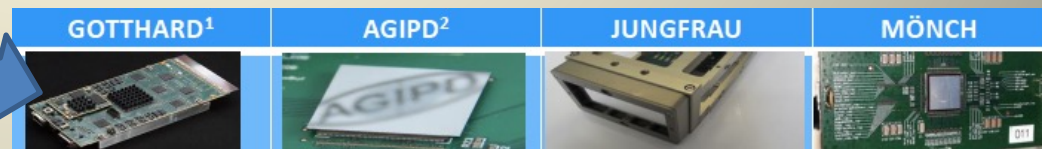
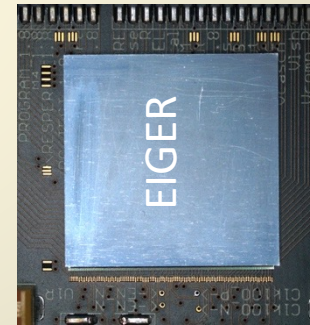
Pixel Electronics



- 1st HEP ASIC in 28 nm
- 4D tracking

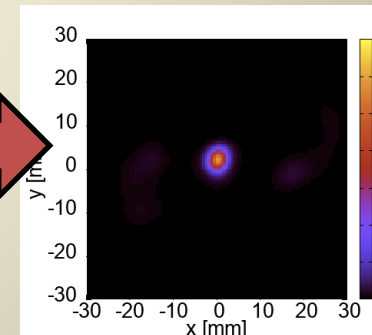
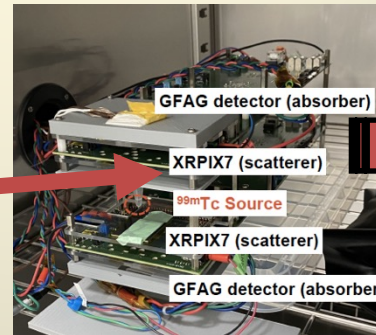
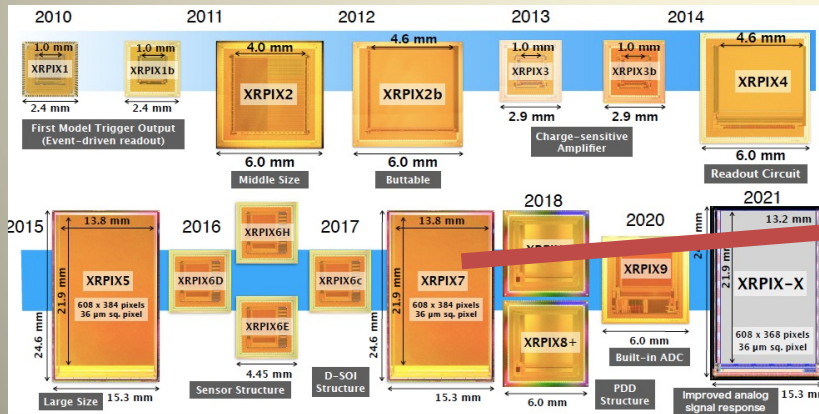
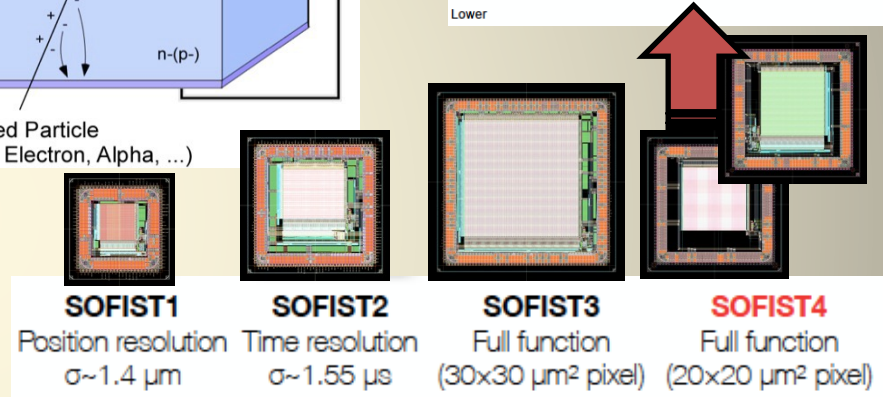
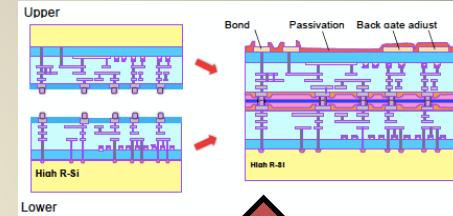
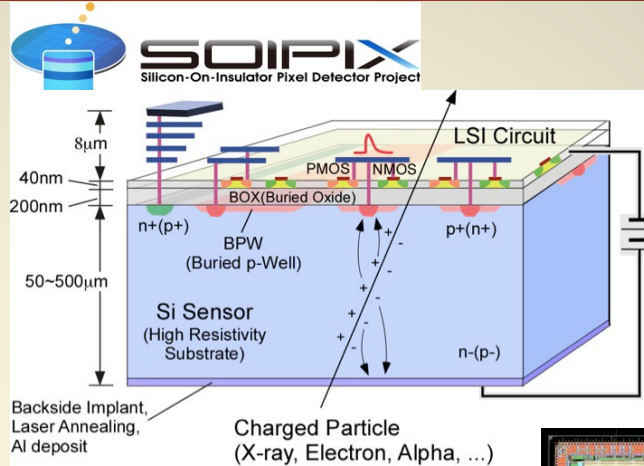


- The Alpine Landscape
 - From HEP to Swiss peaks



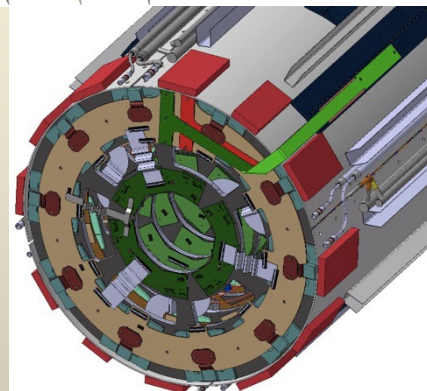
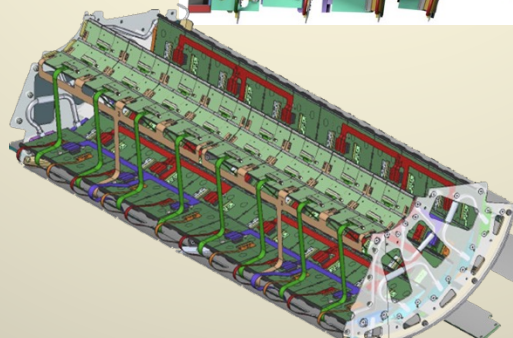
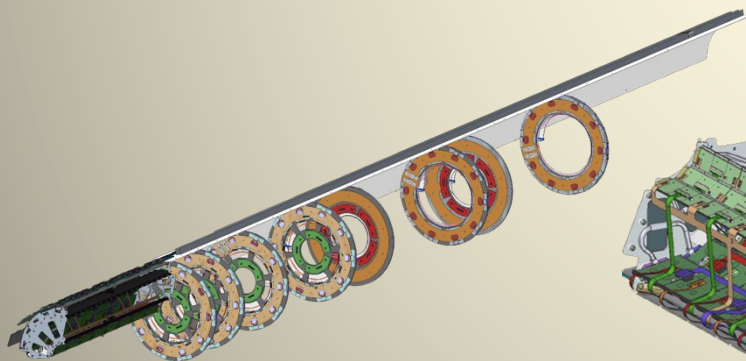
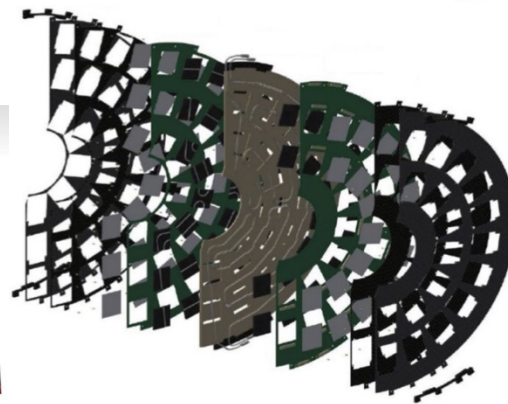
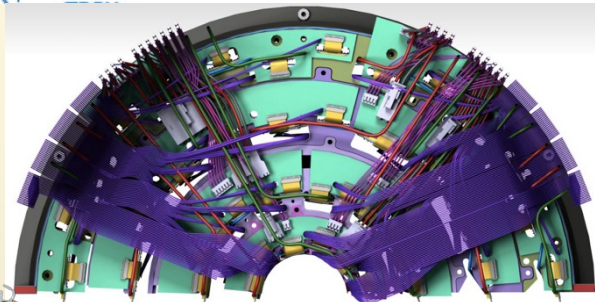
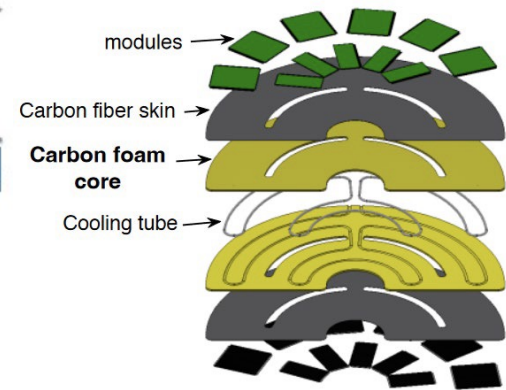
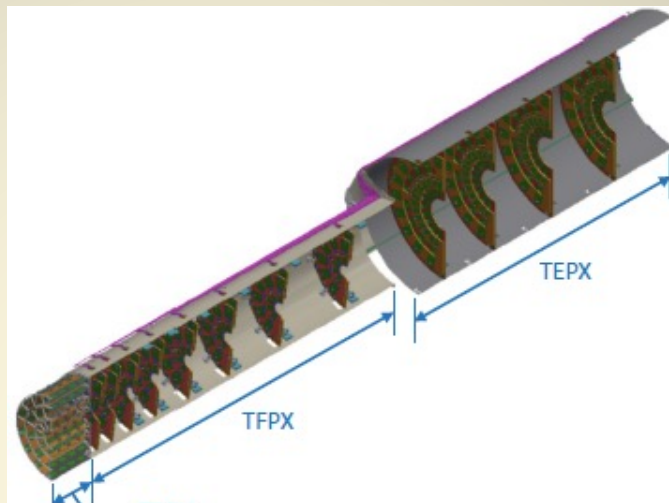
SOI

- Strong Japanese community
 - ILC - SOFIST
 - X-ray Astronomy
 - Compton Camera



Mechanics and Integration

- Vital part of HEP experiment
- Contradicting requirements
 - Power-Cooling
 - Precision-Mass

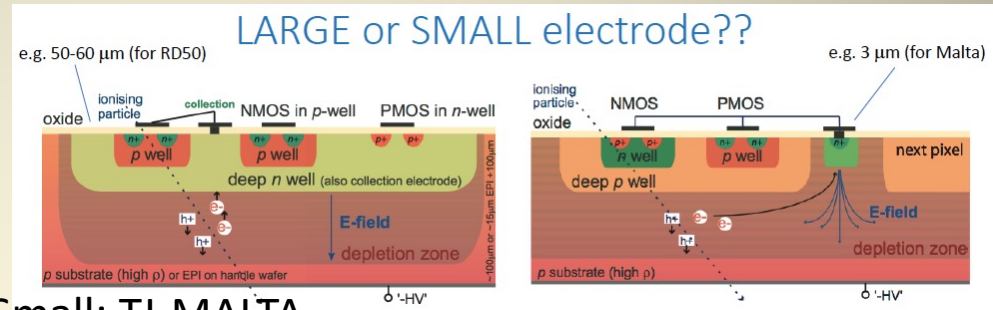


CMOS Detectors

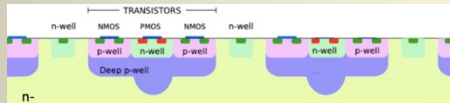
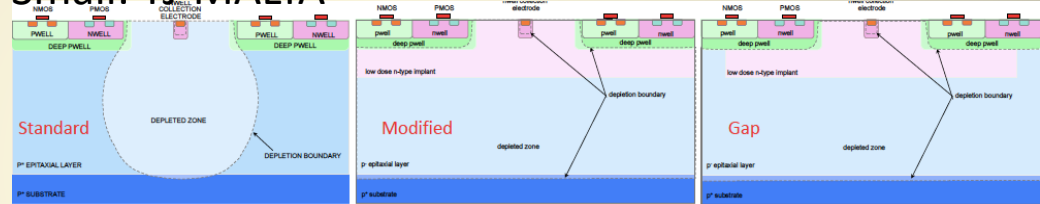
• The future is theirs !

– Small vs. large electrode

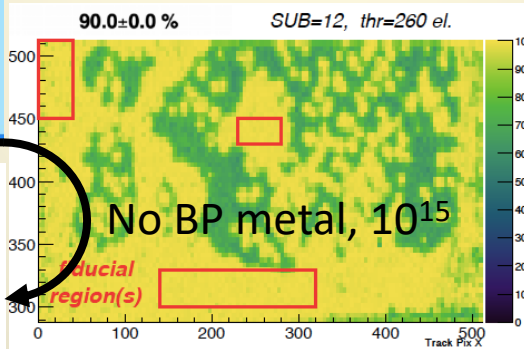
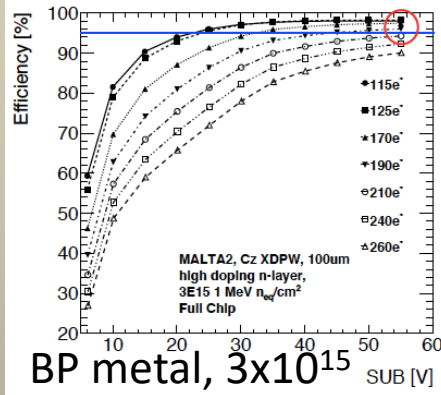
• Can small be radhard enough?



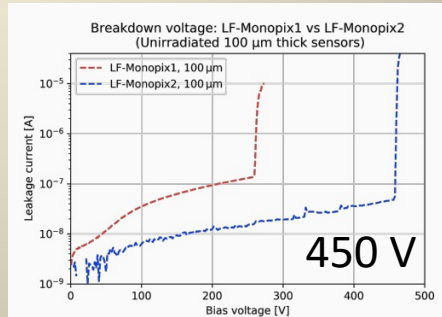
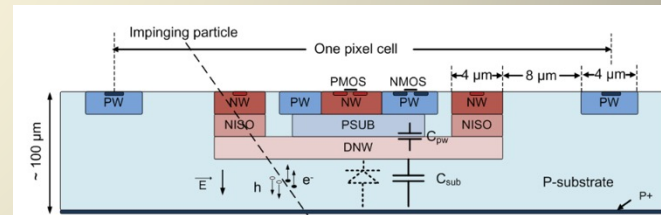
Small: TJ-MALTA



Metallize it!

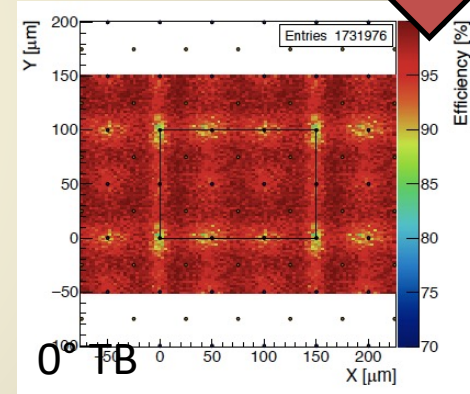
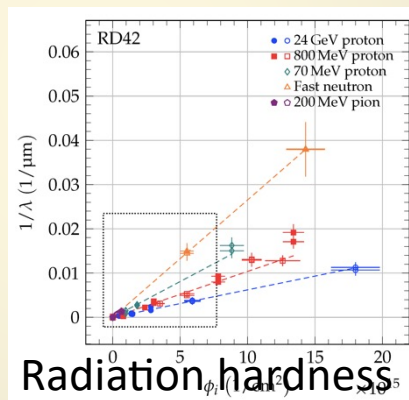
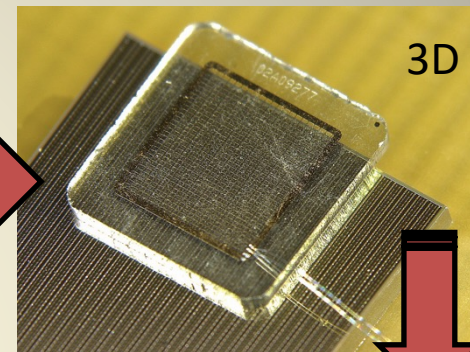
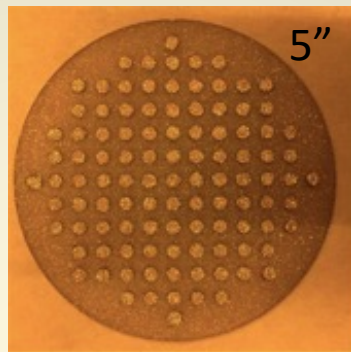


Large: LF-Monopix

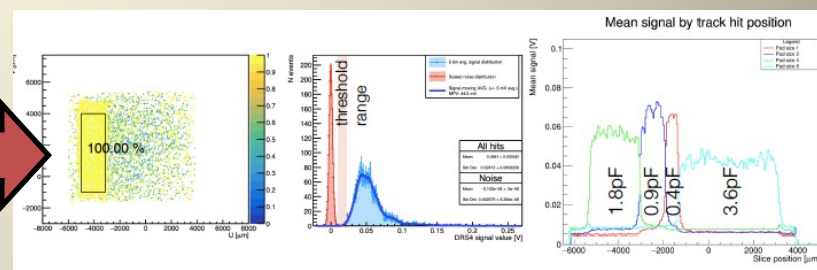
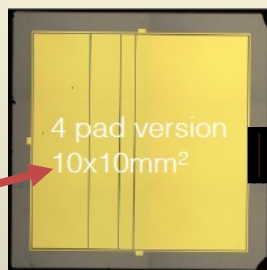
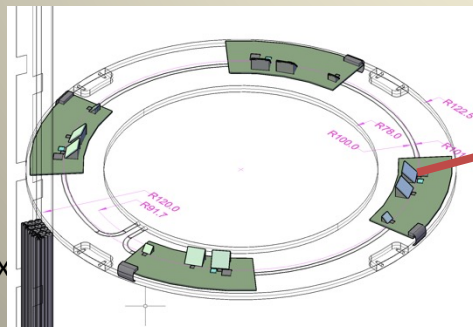


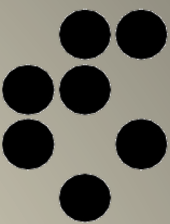
Beyond Silicon - Diamond

- 3D pixel (RD42)
 - Laser drilling of pCVD
 - 100x150, 50x50 μm^2
 - PSI46dig2 chip
 - 99.7% efficiency @70% CCE (@0° !)
 - Production up-scaling ??
 - Radiation hardness summary published



- BCM' (ATLAS ITk)
 - Planar pads 1-50 mm² on 10x10 pCVD
 - Protection and lumi
 - Calypso asynchronous R/O
 - To be installed in inner pixel in 2025





Part II : Outlook

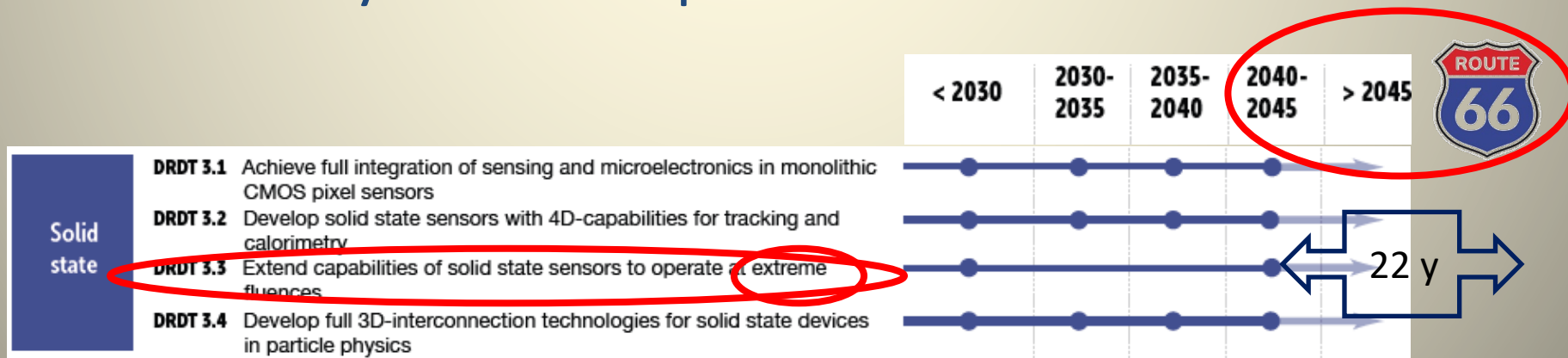
Future (Global) HEP Projects

- The 2020 *European Strategy for Particle Physics* establishes two project initiatives as high-priority
 - “the highest-priority next collider”: “an electron-positron Higgs factory”
 - for the longer term: “a proton-proton collider at the highest achievable energy”, dubbed as the *FCC-hh* project.
- End of 2021 the *ECFA Detector R&D Roadmap* was approved by the CERN Council
 - Long term HEP Detector R&D goals defined
 - Implementation strategy in terms of Detector R&D Collaborations (DRDC) worked out, starting in 2024
- Development cycle towards the use of a new technology in detectors spans over 10 to 20 years.
 - *prospective* detector R&D (“Blue Sky” research) – TRL 1
 - *guided* detector R&D, according to known needs of future projects – TRL 2-5
 - *focussed* detector R&D of approved experiments – TRL 5-7



What's in for Pixels ?

- No doubt we're Solid State...
- We've heard a lot of the 3 out of 4 DRDT's
 - Monolithic CMOS
 - Precision timing → 4D tracking
 - 3D interconnects
- Nothing on **extreme** fluences (DRDT 3.3)
... so let me try to make up for this !



Extreme ?

- What is extreme ?

extreme (ɪk'stri:m)

adj

1. being of a high or of the highest degree or intensity: *extreme cold*; *extreme difficulty*.
2. exceeding what is usual or reasonable; immoderate: *extreme behaviour*.

- A rather subjective measure

- for LHC 10^{15} n_{eq}/cm^2 was considered extreme

- design was 730/fb @14TeV...

- HL-LHC takes it to $nx10^{16}$ (vertex) or even 10^{17} (FW calo)

- 4000/fb @14TeV

- FCC-hh is *specifying* towards 10^{18} for the tracker (*FCC-hh CDR*)

- 30/ab @100TeV

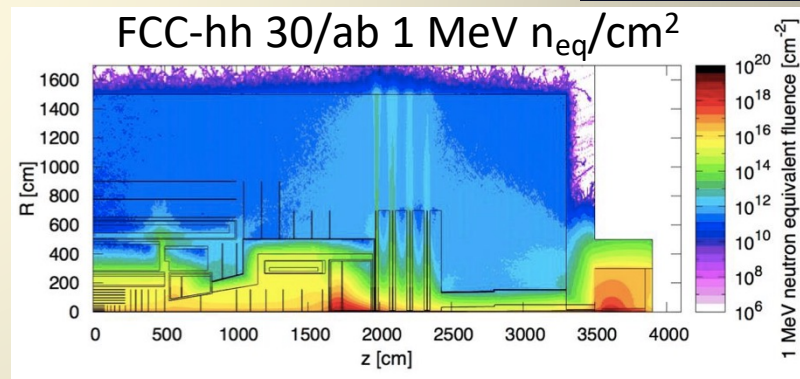
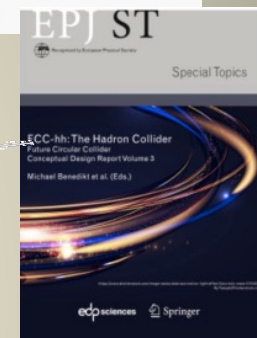
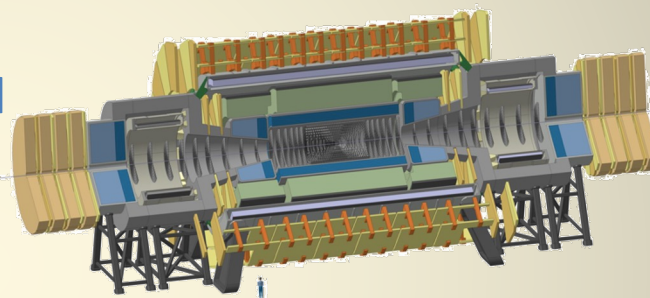
- 300 MGy TID in addition (not addressed)

- Ratio 1:20:600 !

- well, you *need* $\sim 7^2 \approx 50$ in HL/FCC lumi...

- What is the limit of tracking sensors ?

- TRIGA, NPP and ITER are $10^{21} \leftrightarrow 10^{24}$

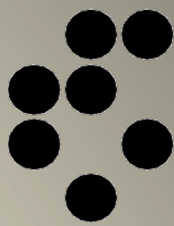


First tracking layer:

- 10 GHz/ cm^2 charged particles
- 10^{18} hadrons/ cm^2 for 30/ab

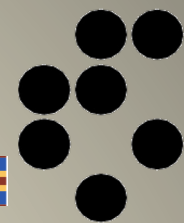


Expectations for $10^{17} n_{eq}/\text{cm}^2$

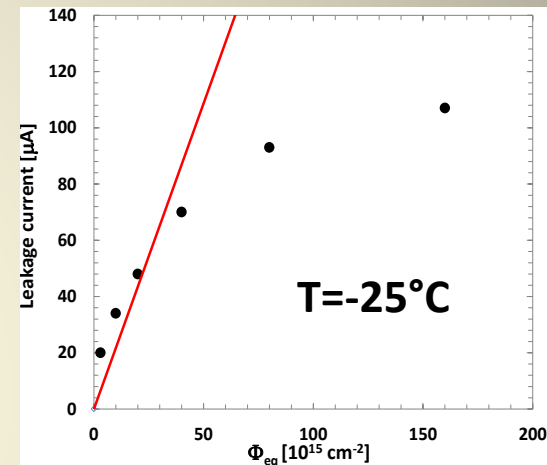


- For a \sim yearly replacement of FCC-hh inner tracker !
 - Or a 2-stage operation 5- \rightarrow 30/ab
- Linear extrapolation from low fluence data
 - Current: $I_{leak} = 4 \text{ A/cm}^3 @ 20^\circ\text{C}$
 - 2 mA/cm^2 (2W @ 1 kV) for 300 μm thick detector @ -20°C
 - Depletion: $N_{eff} \approx 1.5 \times 10^{15} \text{ cm}^{-3}$
 - $FDV \approx 100 \text{ kV}$
 - Trapping $\tau_{eff} \approx 1/40 \text{ ns} = 25 \text{ ps}$
 - $Q \approx Q_0/d v_{sat} \tau_{eff} \approx 80 \text{ e}/\mu\text{m} \cdot 200 \mu\text{m}/\text{ns} \cdot 1/40 \text{ ns} = 400 \text{ e}$ in very high electric field ($\gg 1 \text{ V}/\mu\text{m}$)
- Looks much like *Mission Impossible* (part n...)

CCE measurements up to $1.6 \times 10^{17} \text{ n}_{\text{eq}}/\text{cm}^2$



- n^+p "spaghetti" strips, 300 μm
- Observed signal not at all compatible with expectations
 - Above 3×10^{15} linear $CCE(V_{\text{bias}})$
 - Power law scaling with fluence, $b \approx -2/3$
 - Leakage current "saturating"

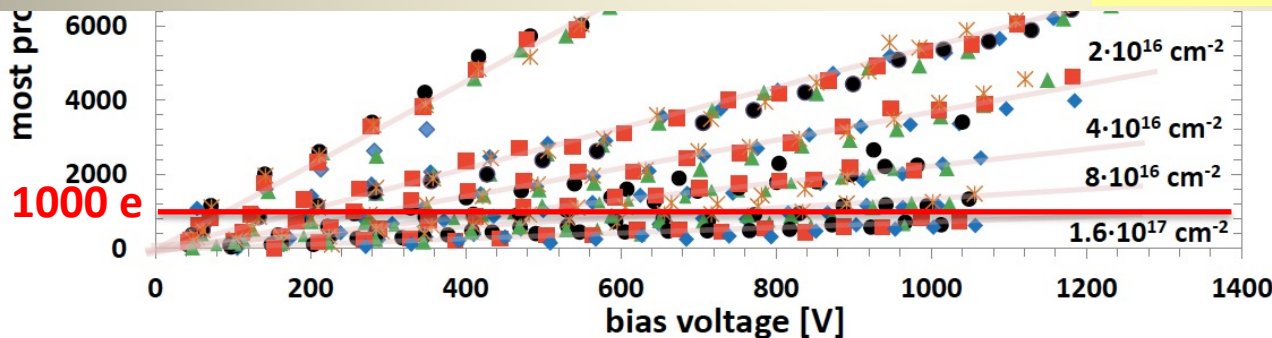


$$Q_{MPV}(V, \Phi) = k \cdot (\Phi / 10^{15} \text{ n}_{\text{eq}}/\text{cm}^2)^b \cdot V$$

$$k = 26.4 \text{ e}_0/\text{V}$$

$$b = -0.683$$

"Magic formula"

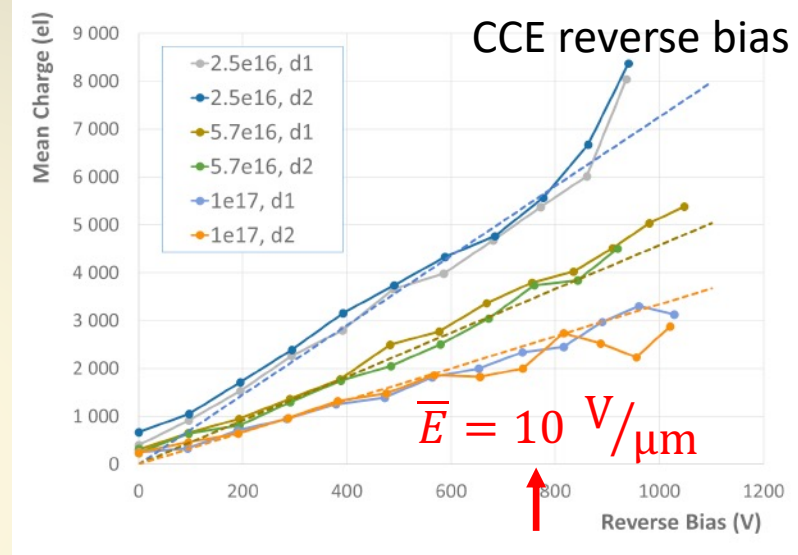


From:

**G. Kramberger et al.,
JINST 8 P08004 (2013).**

More measurements on thin detectors

- 75 μm epi detectors from CNM on low-resistivity substrate
- Irradiated to 0.25, 0.57 and $1.0 \times 10^{17} \text{ n}_{\text{eq}}/\text{cm}^2$
- CCE in reverse and FW
- Annealing 1200 min @ 60°C



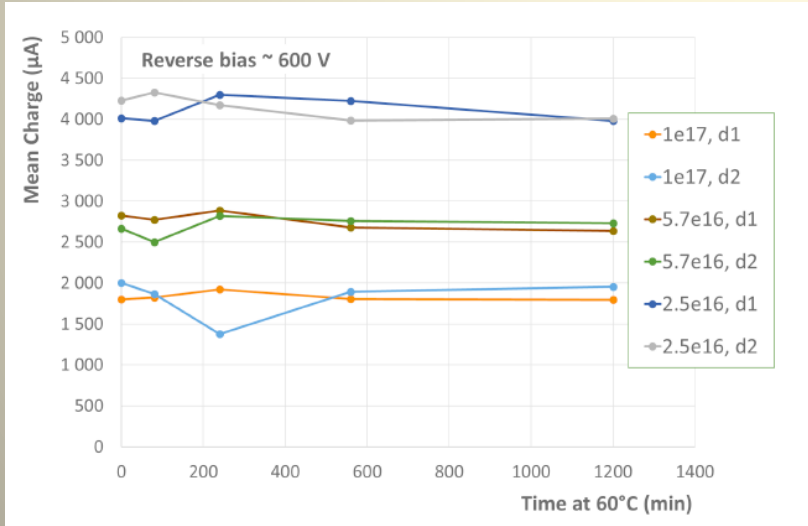
$$Q_{\text{mean}} = k \cdot \phi^b \cdot V$$

$$k_{75} = 44 \text{ e}_0/\text{V}$$

$$b_{75} = -0.56$$

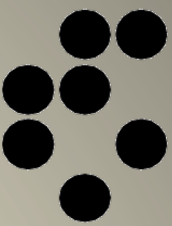
Thinner is better!

From:
**I.Mandić et al.,
 JINST 15 P11018 (2020).**



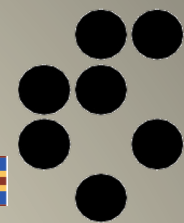


Linear $CCE(V)$??



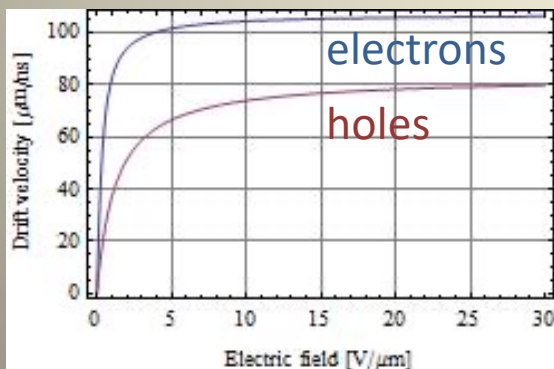
- What could be linear
 - SCR governed $CCE(V)$ after irradiation (\sqrt{V}), highly resistive ENB (\sqrt{V}), without trapping
 - Trapping dominated with non-saturated drift velocity
- What is *not* linear
 - velocity saturation
 - charge multiplication
 - double junction
 - field in ENB
 - ...
- Just a nice coincidence or some physics behind ?
 - look *into* silicon to search for an answer
- Using edge-TCT to probe silicon

Electric Field Measurement

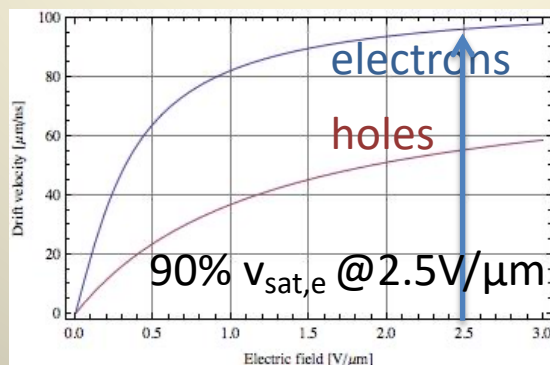


- Initial signal proportional to velocity sum at given detector depth
- Caveats for field extraction
 - Transfer function of electronics smears out signal, snapshot taken at ~ 600 ps
 - Problematic with heavy trapping
 - Electrons with v_{sat} hit electrode in 500 ps
 - Mobility depends on E
 - v saturates for $E \gg 1\text{V}/\mu\text{m}$

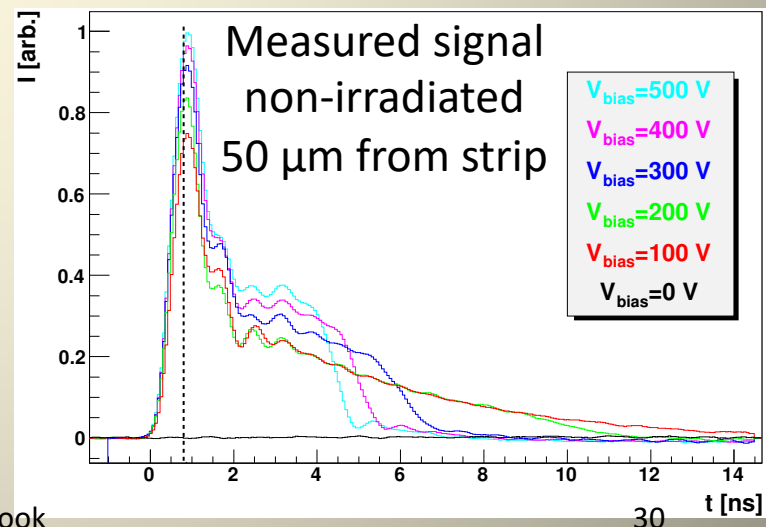
$$\begin{aligned}
 I(t=0) &= q \cdot \vec{v} \cdot \vec{E}_w = \\
 &= N_{e-h} e_0 \cdot (v_e + v_h) / d = \\
 &= N_{e-h} e_0 \cdot (\mu_e + \mu_h) \cdot E(x) / d
 \end{aligned}$$



10th Pixel, 16/12/2022

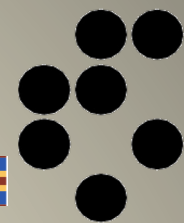


Marko Mikuž: Summary & Outlook

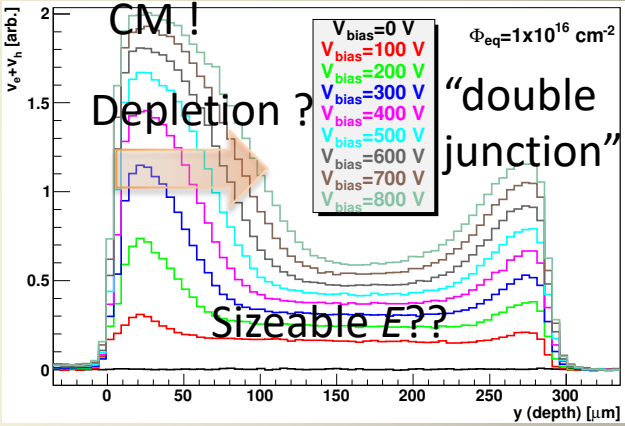
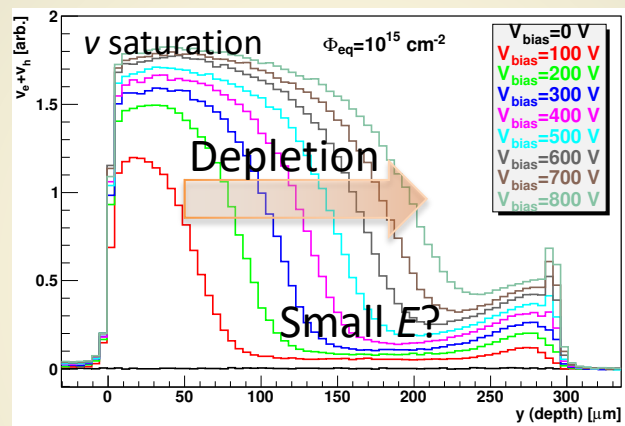
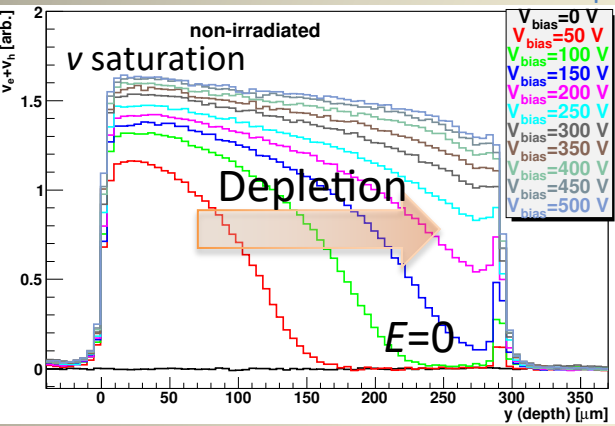


30

Selected Results from Neutrons



- Hamamatsu ATL07 n⁺ mini-strip, FZ p-type, neutron irradiated at JSI TRIGA reactor
 - In steps up to 10¹⁶ n_{eq}/cm²

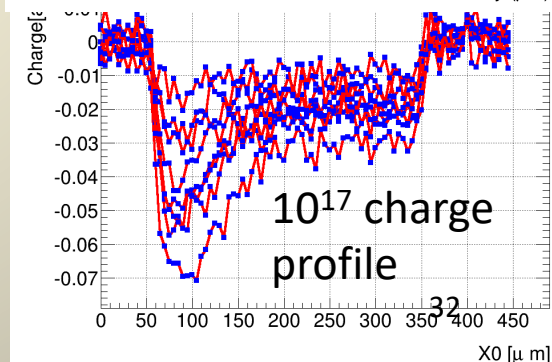
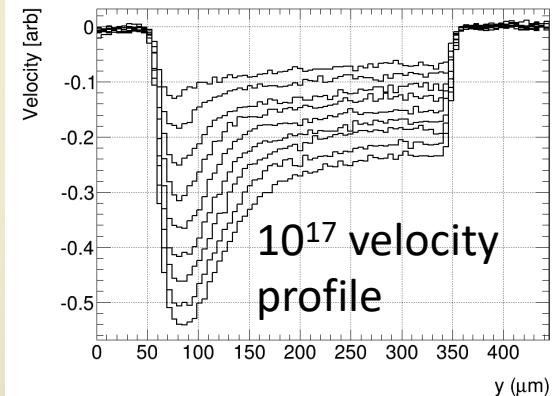
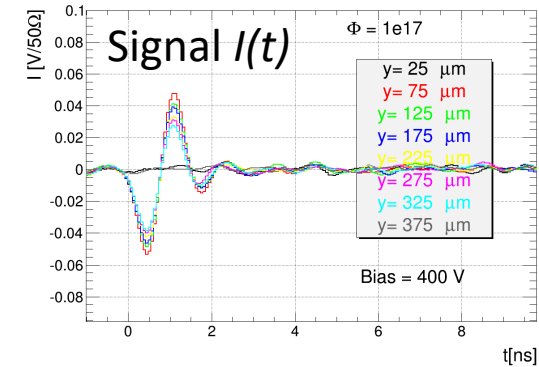


- Very instructive regarding qualitative electric field shape
 - Non-irradiated “by the book” for abrupt junction n⁺p diode
 - SCR and ENB nicely separated, small double junction near backplane
 - Medium fluence ($\Phi=10^{15}$ neutrons): some surprise
 - Smaller space charge than expected in SCR, some field in “ENB”
 - Large fluence ($\Phi=10^{16}$): full of surprises
 - Still lower space charge, sizeable field in “ENB”
 - Charge multiplication (CM) additional trouble for interpretation at large V
- Nice, but let’s try to get *quantitative* !

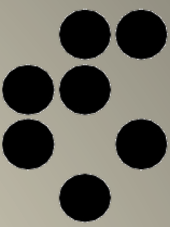
Published in :
**G. Kramberger et al.,
 JINST 9 P10016(2014).**

Extending the Reach

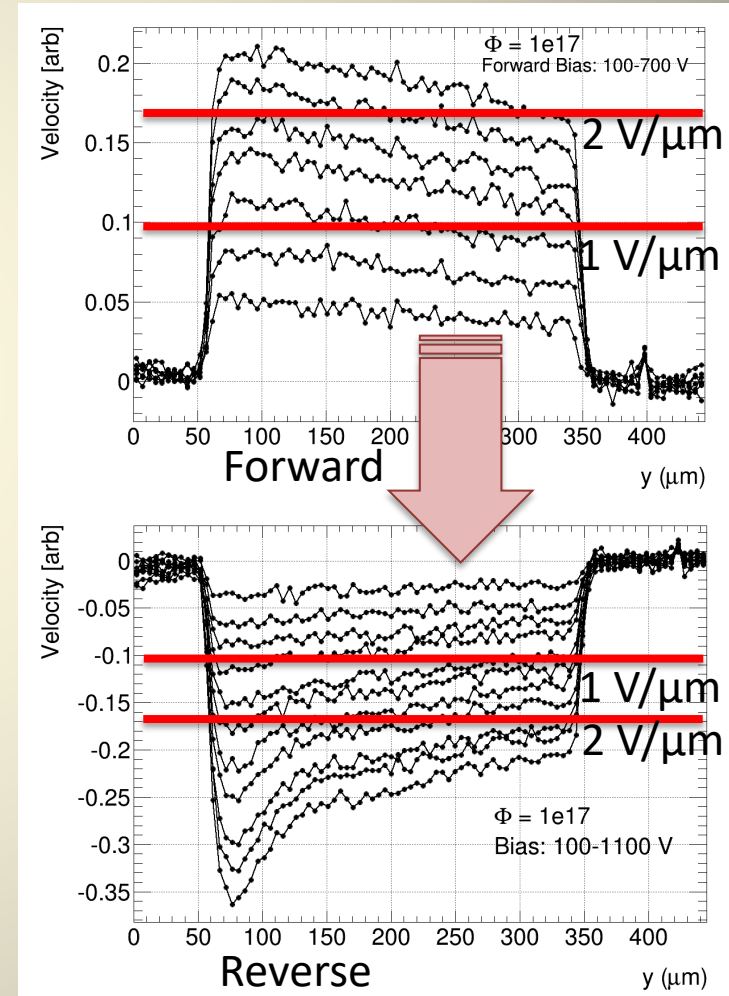
- In 2014 added 5×10^{16} and 10^{17} n_{eq}/cm^2 measurements of the same detector
 - 10^{16} of this fluence fully annealed, the rest 80 min @ 60°C
- Intrinsic feature – signal oscillations
 - period $\sim 5/4$ ns
 - LRC ($C \sim 2\text{pf} \Rightarrow L \sim 20\text{ nH} \sim 1\text{cm}$ of wire)
- Velocity (slope) and charge (integral) yield consistent results
- should be, as $Q \approx Q_0 v_{sum} \tau_{eff} / d$



Absolute Field Measurement

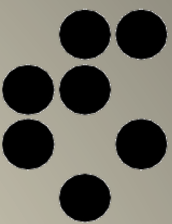


- Solution: *concurrent* forward bias v_{sum} measurements
 - Ohmic behaviour with some linear (field) dependence
 - constant (positive) space charge
 - can use $\int E(y) dy = \bar{E}d = V$ to pin down field scale
 - corrections from $v(E)$ non-linearity small
- Use same scale for reverse bias!
- FW measurements up to 700 V
 - know E scale up to 2.33 V/ μm
 - can reveal $v(E)$ dependence





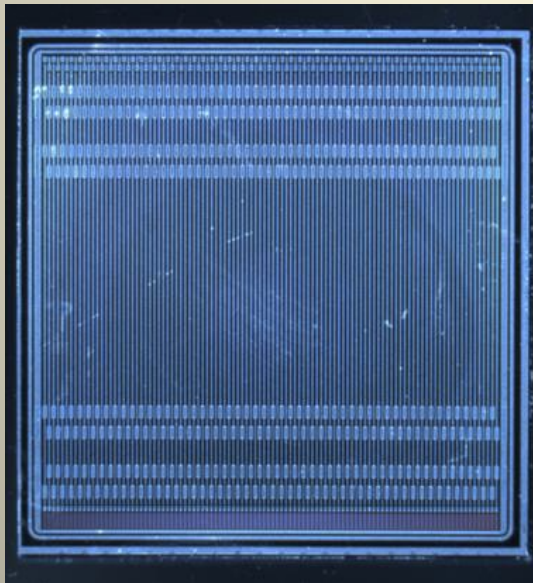
Proton Irradiations



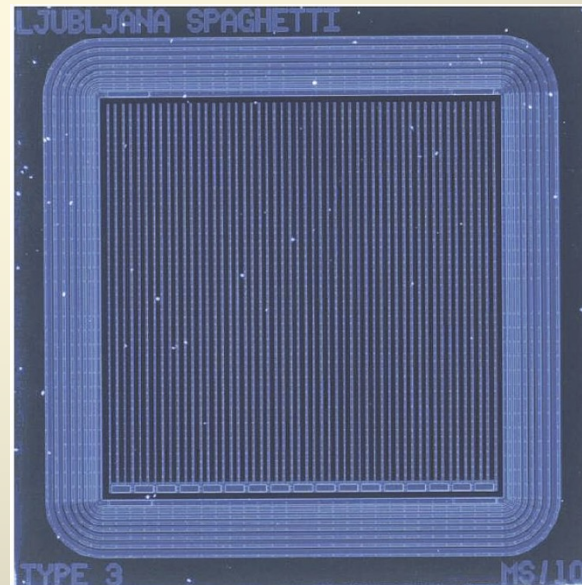
- 5 sample pairs of ATL12 mini-strips irradiated at CERN PS during summer 2015
 - got 0.5, 1.0, 2.9, 11, 28e15 protons/cm², no scanning
 - NIEL hardness factor 0.62
 - thanks to CERN IRRAD team
 - took 41 PS days to reach the highest fluence
- Covers HL-LHC tracker range well
 - does really not look practical for 10¹⁷++
- 2 samples per fluence investigated by E-TCT for all fluences
 - concurrent forward and reverse bias measurements

Additional Irradiations

- $3e17$ n_{eq}/cm^2 , JSI reactor neutrons
 - A12 mini, 7×8 mm², 75 μ m pitch, 300 μ m thick
 - Also to $3e16$, $1e17$
 - Spaghetti: 4×4 mm², n-on-p, strip pitch 80 μ m, 300 μ m thick, strips connected together at side
 - $1.6e17$ received previously, $4.6e17$ total

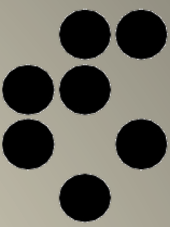


A12

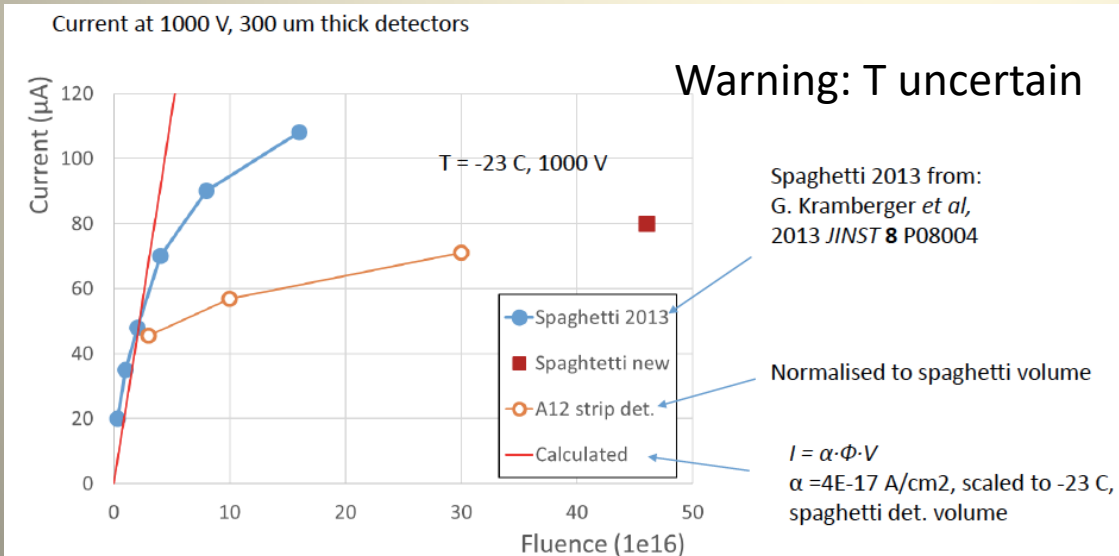
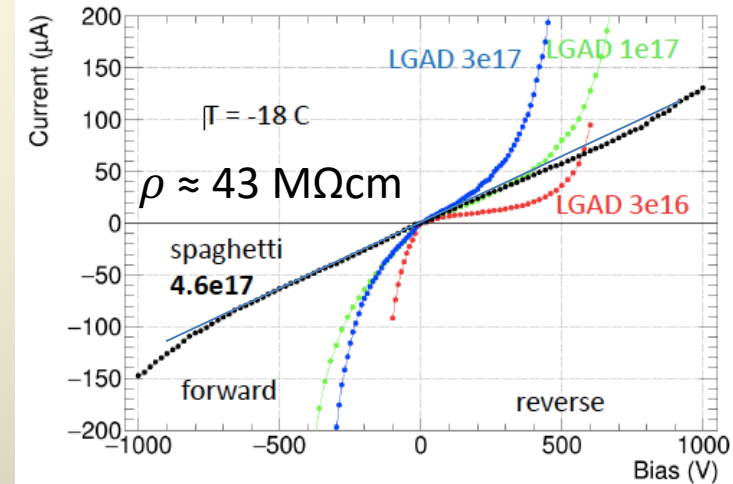
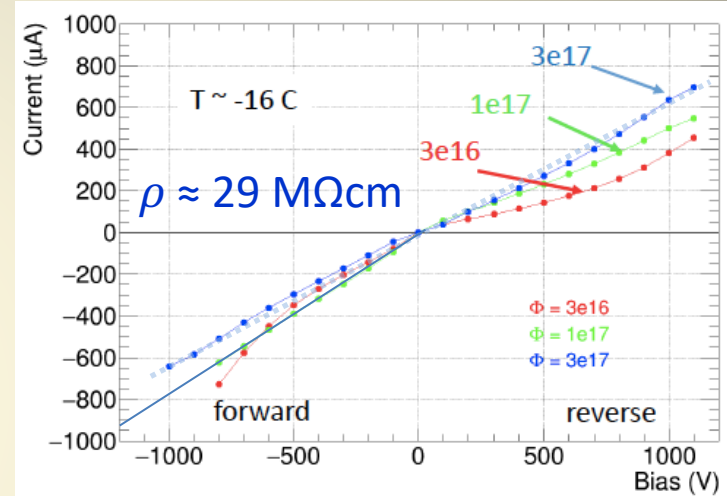


Spaghetti

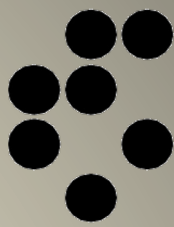
Basic Measurements



- I - V for 3&4.6e17 looks very linear with little difference between reverse/FW bias
 - No breakdown, as observed in LGAD's
- I @1000 V does not scale linearly with fluence !
 - Not governed by generation current ?
- Tried to measure 4.6e17 spaghetti CCE with ^{90}Sr
 - No signal above background observed up to 320 V
 - Magic formula predicts 120e for 4.6e17 @320 V



Mobility Considerations FW bias

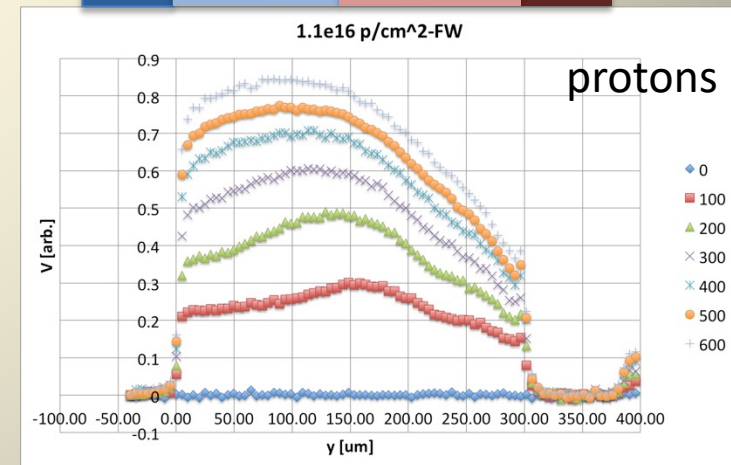
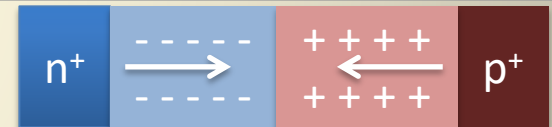
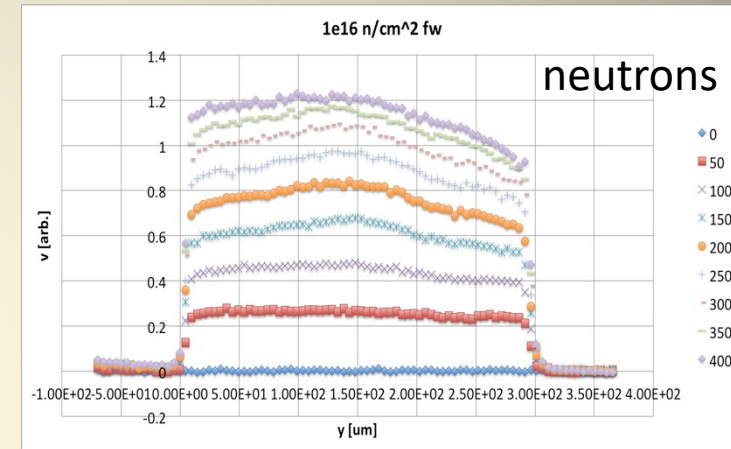


- For forward bias can extract $v(E)$ up to a scale factor
- Observe less saturation than predicted
- Model with

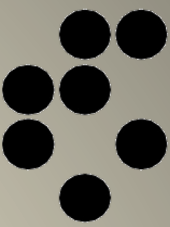
$$v_{sum}(E) = \frac{\mu_{0,e}E}{1 + \frac{\mu_{0,e}E}{v_{e,sat}}} + \frac{\mu_{0,h}E}{1 + \frac{\mu_{0,h}E}{v_{h,sat}}}$$

- keep saturation velocities at nominal values @-20°C ($v_{e,sat} = 107 \mu\text{m/ns}$; $v_{h,sat} = 83 \mu\text{m/ns}$)
- float (common) zero field mobility degradation
- fit $v(E)$ for $\phi_n \geq 5 \times 10^{15}$ and $\phi_p \geq 3 \times 10^{15}$

n.b. FW profiles less uniform for lower fluences & protons; departures from average field still small, corrections $O(\%)$

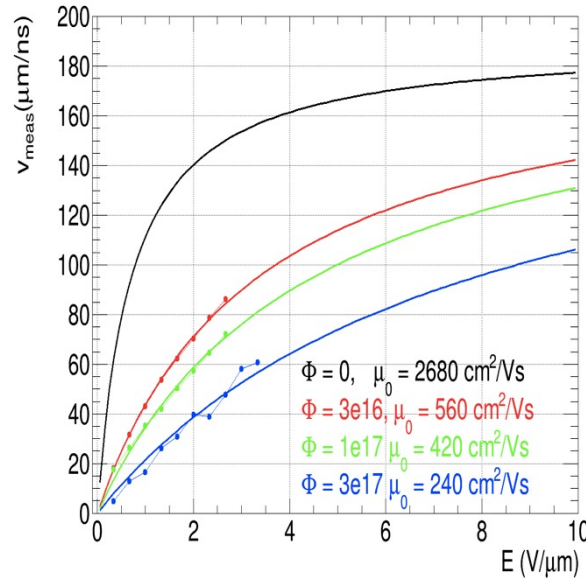
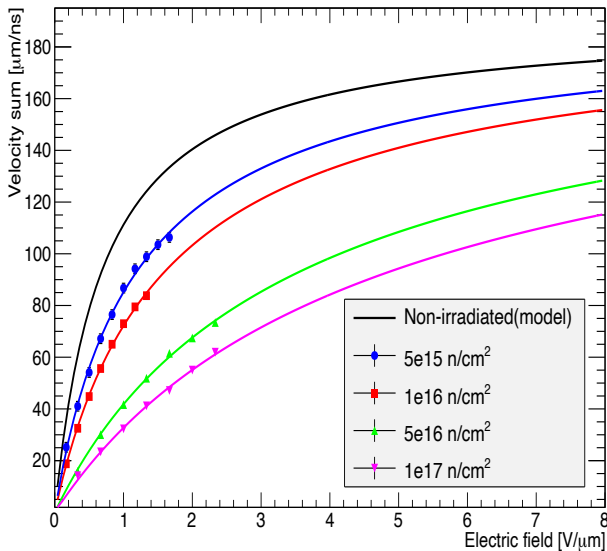


Mobility Fits

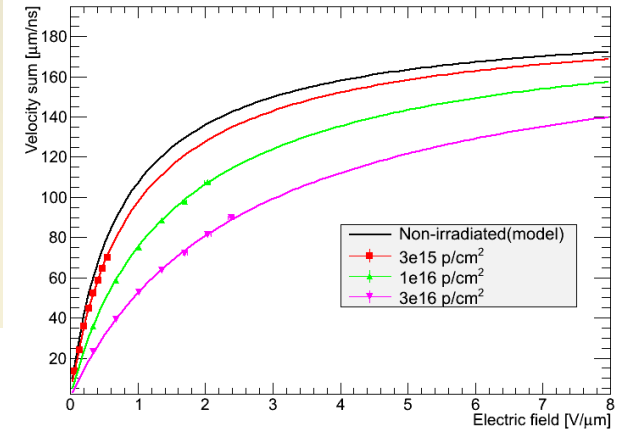


- Data fits model almost perfectly
 - μ_0 degradation the only free parameter, scale fixed by $v_{sum,sat}$
 - At $3e17$ E range too limited ($v(E)$ linear), regard result as upper limit

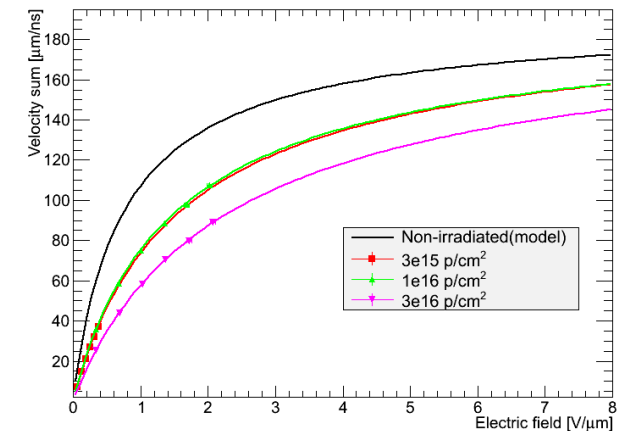
Mobility neutrons



Mobility protons A

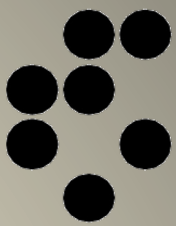


Mobility protons B





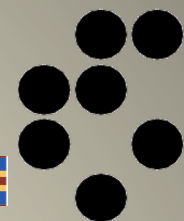
Mobility Results



- Fit to $v_e + v_h$ with common mobility degradation factor
 - factor of **2** at $10^{16} n_{eq}/cm^2$, **6** at $10^{17} n_{eq}/cm^2$, **>10** at $3 \times 10^{17} n_{eq}/cm^2$
 - need **2x/6x/>10** higher E to saturate v !
- ☠️ correspondingly higher E for charge multiplication !

Φ_n	$\mu_{0,sum}$	Φ_p	$\mu_{0,sum}$
[$10^{15} n_{eq}/cm^2$]	[cm^2/Vs]	[$10^{15} n_{eq}/cm^2$]	[cm^2/Vs]
non-irr (model)		2680	
5	1661 ± 134	1.6	2063 ± 188
10	1238 ± 131	6.1	1337 ± 47
30	560	15.4	817 ± 42
50	555 ± 32		
100	407 ± 40		
100	420	T=-20°C	
300	<240		

Mobility Analysis



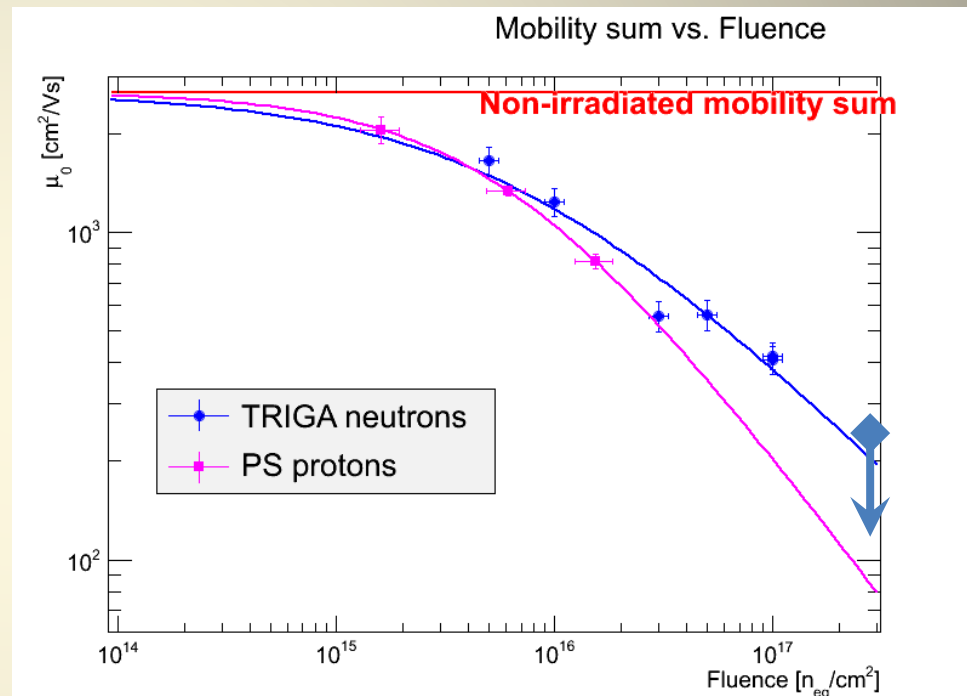
- Mobility governed by hard scattering on acoustic phonons and traps

$$\frac{1}{\tau} = \frac{1}{\tau_{ph}} + \frac{1}{\tau_{trap}}$$

- Fit mobility dependence on fluence with a power law

$$\mu_{0,sum}(\Phi) = \frac{\mu_{0,sum,phonon}}{1 + \left(\frac{\Phi}{\Phi_{1/2}}\right)^a}$$

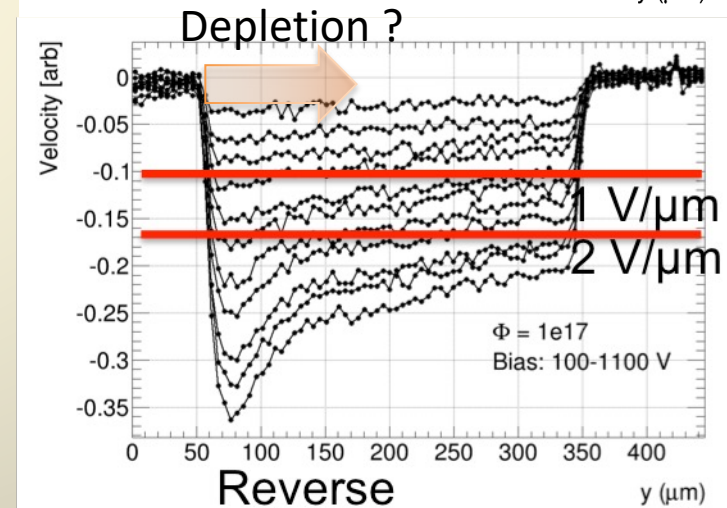
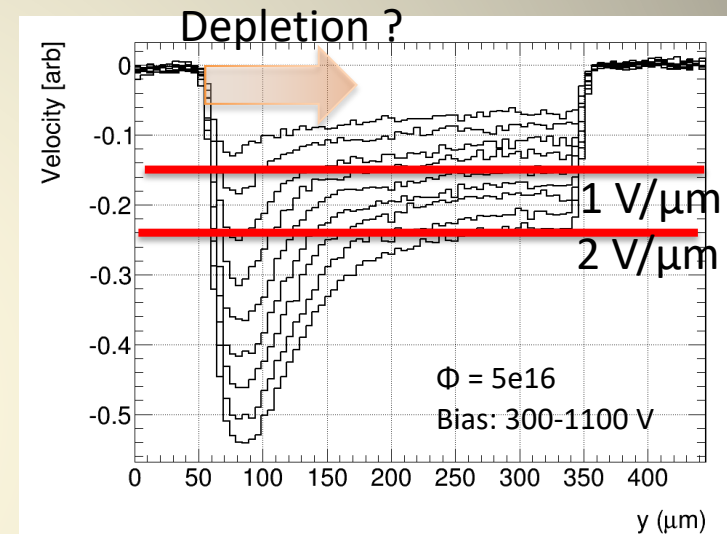
- Fits perfectly, value of a close to linear
 - 10% error assumed for all neutron data
- At same NIEL, mobility decrease worse for protons
 - NIEL violation? Large errors?



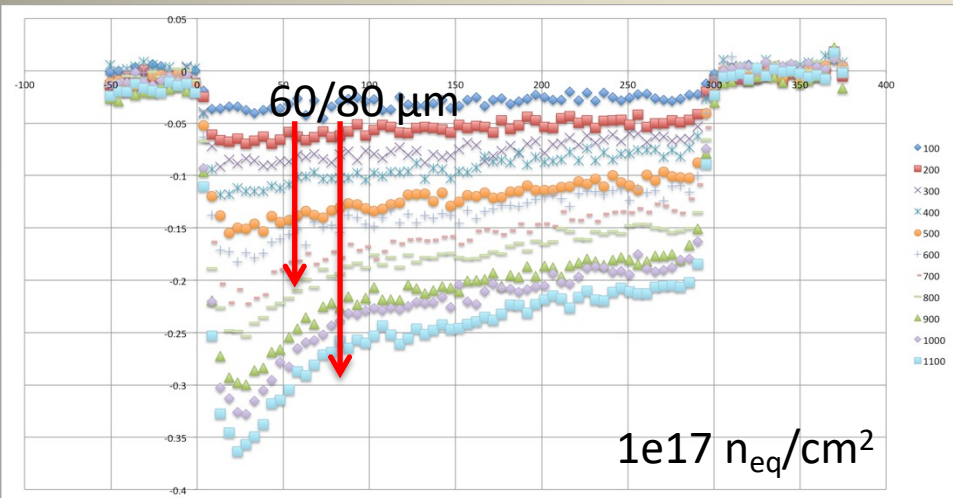
Irradiation particle	a	σ_a	$\Phi_{1/2} / 10^{15}$	$\sigma_{\Phi_{1/2}} / 10^{15}$
Reactor neutrons	-0.68	0.08	6.9	1.7
PS protons	-0.90	0.19	6.1	1.0

Reverse Bias Field Profile

- Two distinct regions at high biases
 - Large region from backplane with (small) slope in the field
 - constant (small, negative) space-charge
 - $E = j \cdot \rho$ at junction ? like “ENB” ?
 - indication of thermal (quasi)equilibrium: $np = n_i^2$?
 - thus no current generation ?
 - Small region at junction building up with bias
 - depleted space-charge region ?
 - source of generation current ?



SCR Consistency

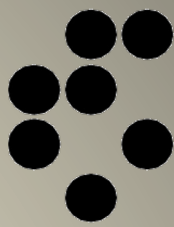


- Hard to estimate SCR extent, especially at lower bias and highest fluence
- A crude estimate
 - $5 \times 10^{16} n_{eq}/\text{cm}^2$:
~80 μm @ 600 V; ~120 μm @ 1000 V
 - $10^{17} n_{eq}/\text{cm}^2$:
~60 μm @ 600 V; ~80 μm @ 1000 V

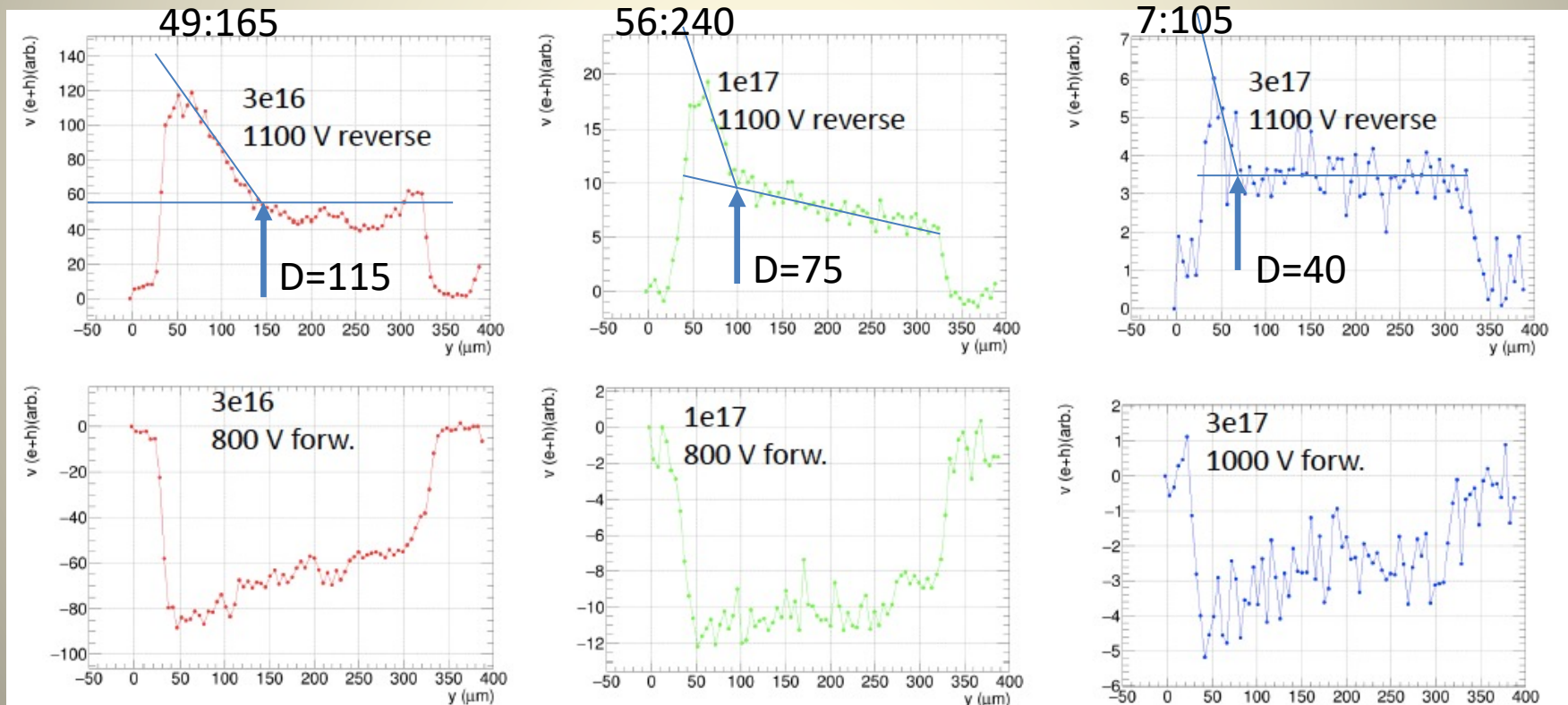
- Predicted/measured currents
 - $5 \times 10^{16} n_{eq}/\text{cm}^2$: 300/300 μA @ 600 V; 400/500 μA @ 1000 V
 - $10^{17} n_{eq}/\text{cm}^2$: 400/300 μA @ 600 V; 500/600 μA @ 1000 V
 - Not compatible with linear I - V at 3 & 4.6e17 – pure resistor ?
- Reasonable agreement with current generated exclusively in SCR
 - n.b. - current “saturation” observed @1000V in *JINST 8 P08004 (2013)*
- Acceptor introduction rates: $g_c \approx 6/4 \times 10^{-4} \text{ cm}^{-1}$
 - substantial part (up to 80 %) of voltage drop “spent” in “ENB”
 - matches well data in *JINST 9 P10016(2014)* (up to 10^{16})



ATL12 up to $3e17$

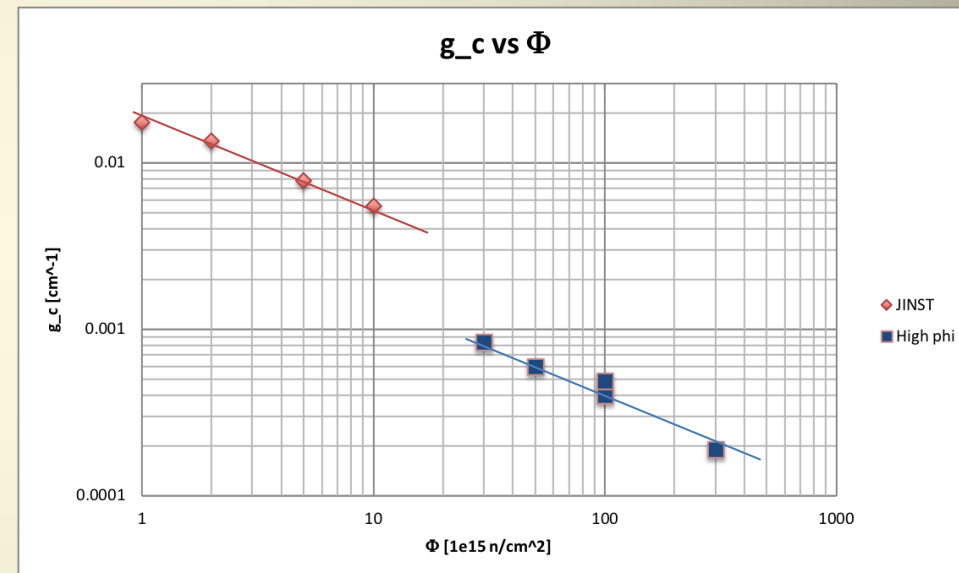


- Estimate of SCR width 115 \rightarrow 75 \rightarrow 40 μm
- V_{drop} in SCR only 23 \rightarrow 19 \rightarrow 6 % of 1100 V

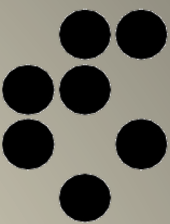


Acceptor introduction in SCR

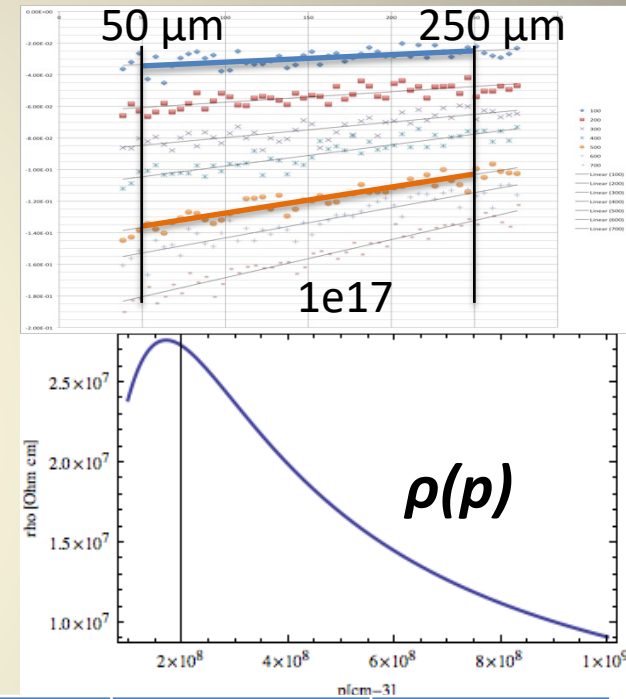
- Stable acceptor introduction rate g_c drops by nearly two orders of magnitude from low fluences to 3×10^{17}
 - Observed up to 10^{16} in *JINST 9 P10016(2014)*
 - Looks like a power law
 - g_c in JINST not taking into account voltage drop out of SCR – higher values of g_c



“ENB” Consistency



- Space charge in “ENB” rising with bias, e.g. for $10^{17} n_{eq}/cm^2$
 - 1.6×10^{11} @ 100 V, $9.2 \times 10^{11} cm^{-3}$ @ 500V
 - c.f. $\sim 4 \times 10^{13} cm^{-3}$ in SCR
 - negative space charge, like in SCR
- Resistivity from $\rho = j/E$ @ 100 V
 - maximum $\rho(p) \approx 2.8 \times 10^7 \Omega cm$ using nominal mobilities @ $p \sim 2 \times 10^8 cm^{-3}$
 - all measured values exceed this limit
 - compatible with measured mobility sum and $p \sim O(10^9) cm^{-3}$
 - Compatible also with ρ from $I-V$ for 3 & 4.6e17

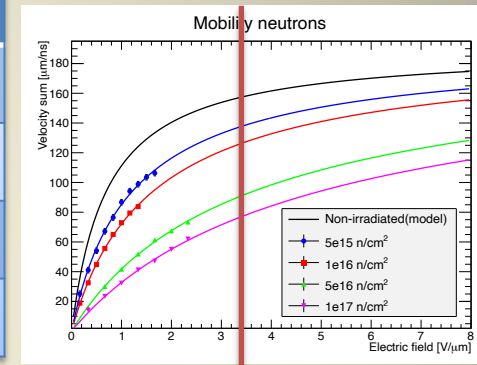


Φ	ρ	p
$[n_{eq}/cm^2]$	$[10^7 \Omega cm]$	$[10^9 cm^{-3}]$
1e16	3.3	0.5
5e16	3.0	1.5
1e17	2.8	2.1

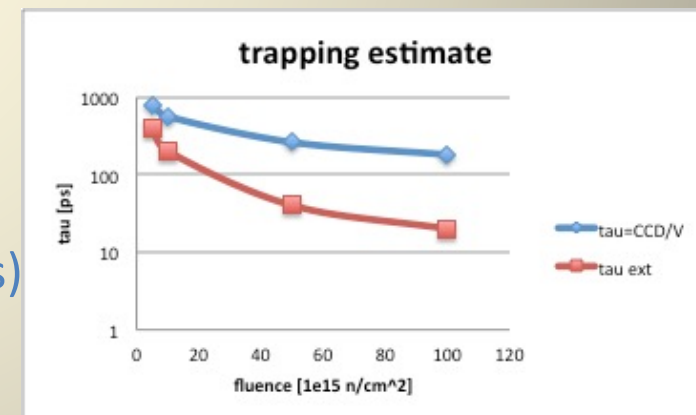
Trapping analysis

- Take v_{sum} at average $E = 3.3 \text{ V}/\mu\text{m}$
- Calculate CCD from “magic formula”

Φ [1e15]	5	10	50	100
$v_{sum}(3.3 \text{ V}/\mu\text{m})$	137	126	90	77
$CCD_{1000 \text{ V}} [\mu\text{m}]$	110	70	23	14
$\tau \approx CCD/v$ [ps]	800	560	260	180
τ_{ext} [ps]	400	200	40	20

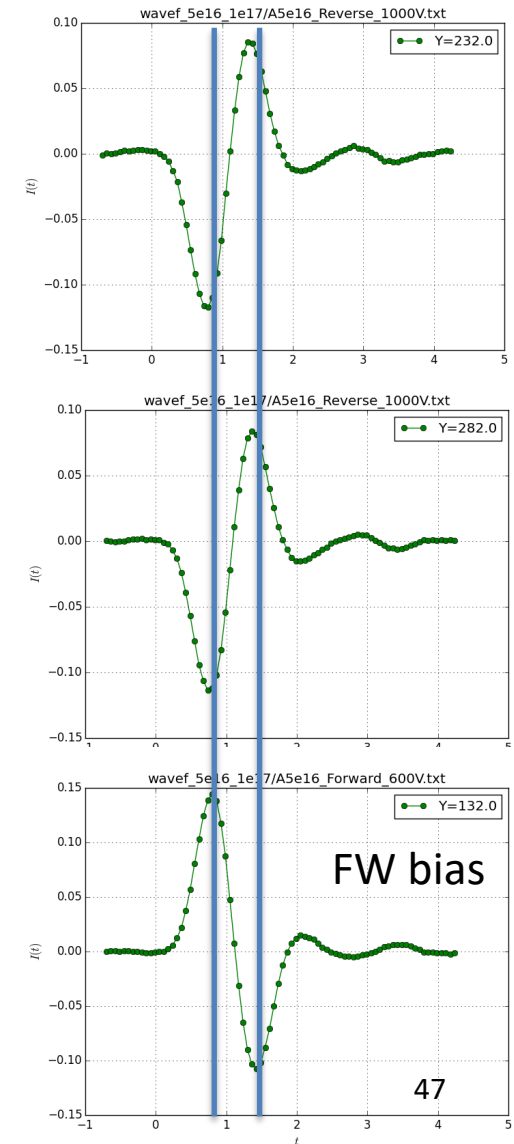
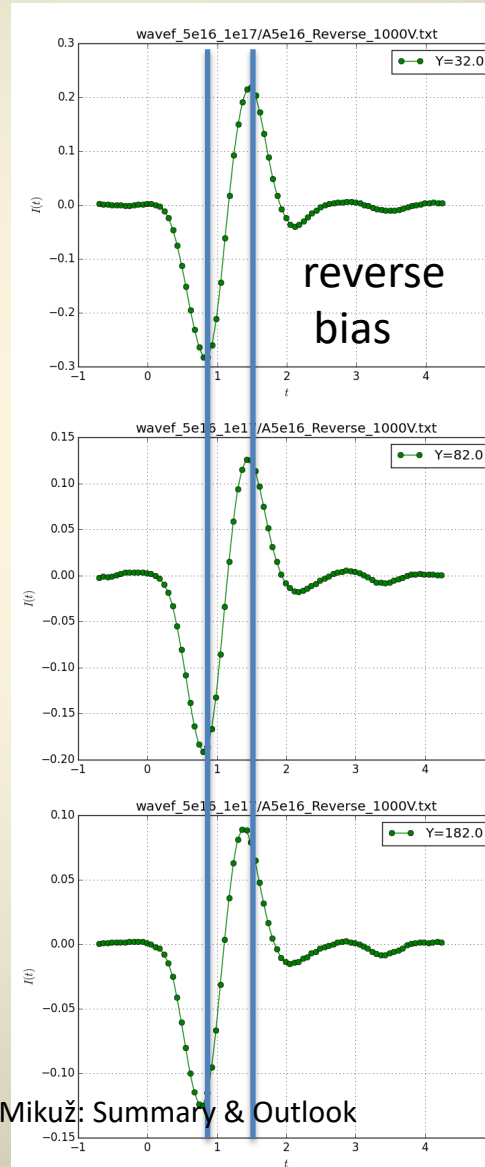


- Implies factor of 6-9 less trapping at highest fluences
 - lowest fluence still x2 from extrapolation
 - weak dependence on fluence as anticipated
 - CM would effectively shorten trapping times
 - not good when large E variations ($v(E)$ saturates)
 - not good when $CCD \approx$ thickness (less signal at same τ)



Trapping – position dependence ?

- Waveforms plotted every 50 μm in detector depth for reverse bias at 1000 V
- Forward bias in middle of detector added at 600 V
- Very little, if any, wf dependence on position observed
- Trapping not position dependent !?



Trapping revisited

- From *I. Mandić et al., JINST 15 P11018 (2020)*

– FW bias CCE estimated by

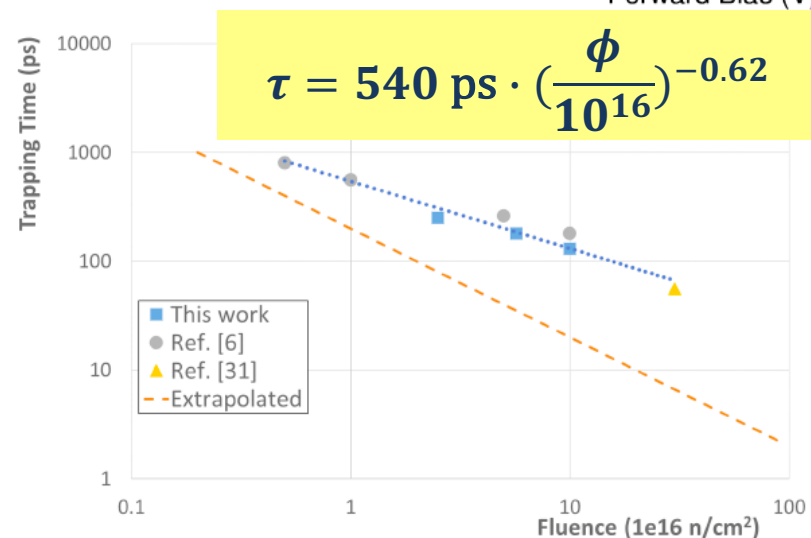
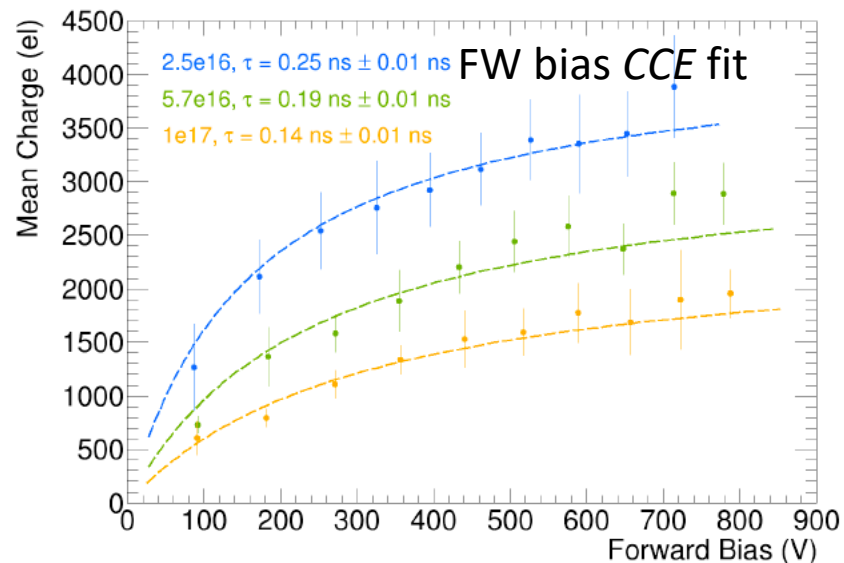
$$Q = \frac{\Delta Q}{\Delta x} \cdot v \cdot \tau$$

- $v(E)$ with fluence dependent μ
- constant $E=V/D$ (FW)

😊 Order of magnitude smaller than extrapolated !

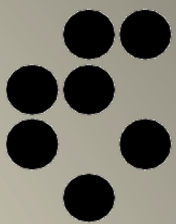
😊 Agrees with estimates from reverse bias CCE

- Trapping independent of bias, seen in wave-forms





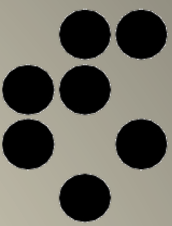
Summary



- Measurements performed on Si detectors irradiated to extreme fluences
 - Neutrons from 10^{15} to 4.6×10^{17} $n_{\text{eq}}/\text{cm}^2$, PS protons from 5×10^{14} to 3×10^{16} p/cm^2
 - Velocity vs. electric field impact observed and interpreted as reduction of zero field mobility
 - Zero field mobility follows power law with $|a| \leq 1$, $\Phi_{1/2} \approx 10^{16}$ n/cm^2
 - Protons degrade mobility more than neutrons
 - Induces resistivity increase in-line with measured I - V
 - Exhibits adverse effect on charge multiplication !
 - Simple field profile for very high neutron fluences
 - Diminishing SCR and highly resistive ENB
 - Effective acceptor introduction rates reduced by factor ~ 100 wrt low fluences
 - Current much lower than anticipated. Generated in SCR only ? Ohmic at highest fluences...
 - Trapping estimates for very high neutron fluences
 - from charge collection in FW and reverse bias
 - from waveforms
 - All estimates point to severe non-linearity of trapping with fluence, 10x lower at 10^{17}
 - Trapping appears independent of electric field
- Conclusion: ***Low fluence extrapolations do not work at all !***
... go out and ***measure*** to get anything working at ***extreme*** fluences !!!

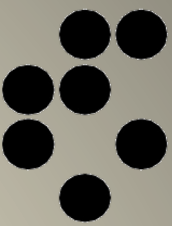


Implications for DRDT 3.3



- Basic bulk silicon properties in the fluence range to master are the prerequisite to any inner tracking detector design for *FCC-hh*
- They need to be ***measured***
 - Only pioneering consistency checks done so far
- Need resources far beyond current ones
 - Facilities
 - Measurement techniques
 - Peopleat least for the first ~5 of the 20 years
- New DRD Collaboration based on the RD50 research line essential for achieving the goal
 - EU funding should help to rise funds at national level

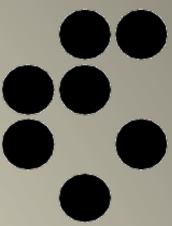
Conclusion



NOTHING IS
IMPOSSIBLE,
THE WORD
ITSELF SAYS
“I’M POSSIBLE”!
- AUDREY HEPBURN

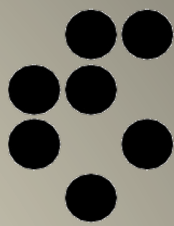


Backup Slides



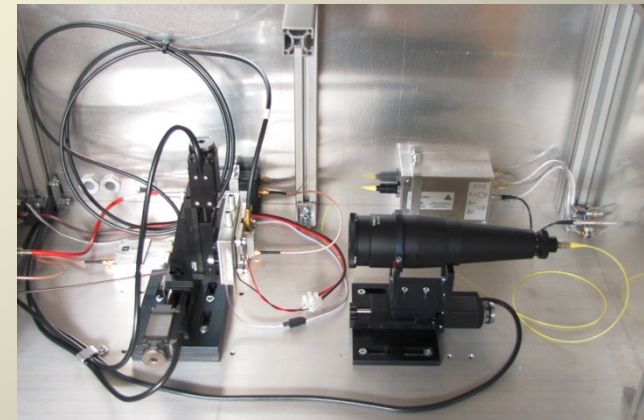
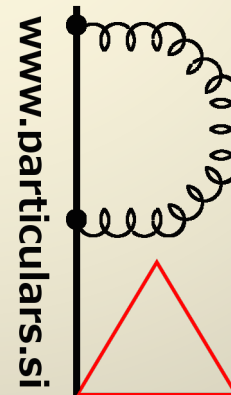
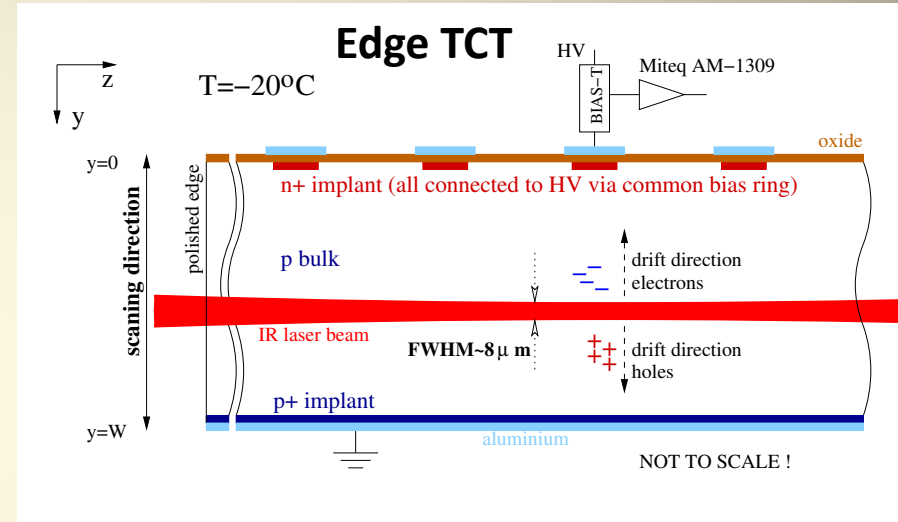


Edge TCT

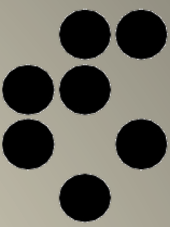


• Edge-TCT

- Generate charges by edge-on IR laser perpendicular to strips, detector edge polished
- Focus laser under the strip to be measured, move detector to scan
- Measure induced signal with fast amplifier with sub-ns rise-time (Transient Current Technique)
- Laser beam width $8\ \mu\text{m}$ FWHM under the chosen strip, fast (40 ps) and powerful laser
 - Caveat – injecting charge under all strips effectively results in constant weighting (albeit not electric !) field



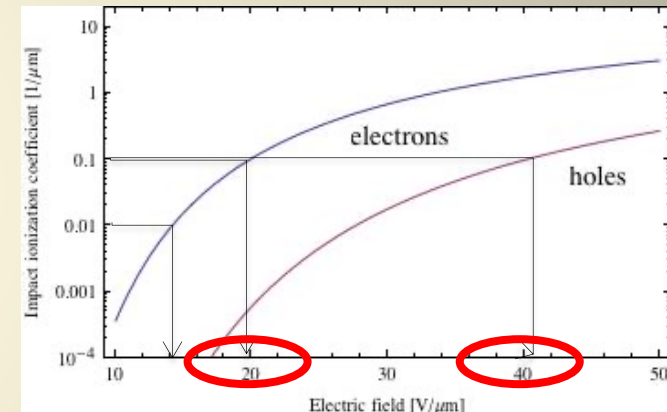
Charge Multiplication



- Multiplication is textbook physics
 - e.g. S.M. Sze, Physics of Semiconductor Devices, Wiley, New York, 1981
 - Ch 1.6.4 High-Field Property
 - Velocity saturation, impact ionization
 - Ch 2.5.3 Avalanche Multiplication
 - Junction break-down
- Measured impact ionization
 - Electrons create 1 pair in 10 μm at $E \sim 20 \text{ V}/\mu\text{m}$ (100 μm at 14 $\text{V}/\mu\text{m}$), holes need $E \sim 40 \text{ V}/\mu\text{m}$
 - Holes need $\sim 1 \text{ mm}$ for pair creation at $E \sim 20 \text{ V}/\mu\text{m}$
 - Neglect hole multiplication in signal creation altogether
 - Need to invoke hole multiplication for junction breakdown
- $\alpha_e \gg \alpha_h$ - Nature gentle to us (in silicon)
 - Large range in E where electrons multiply without inducing breakdown
 - But beware of (too) high electric fields !

$$\alpha_{e,h}(E) = \alpha_{e,h}^{\infty} e^{-b_{e,h}/E}$$

A. G. Chynoweth, Phys. Rev. 109, 1537(1958).



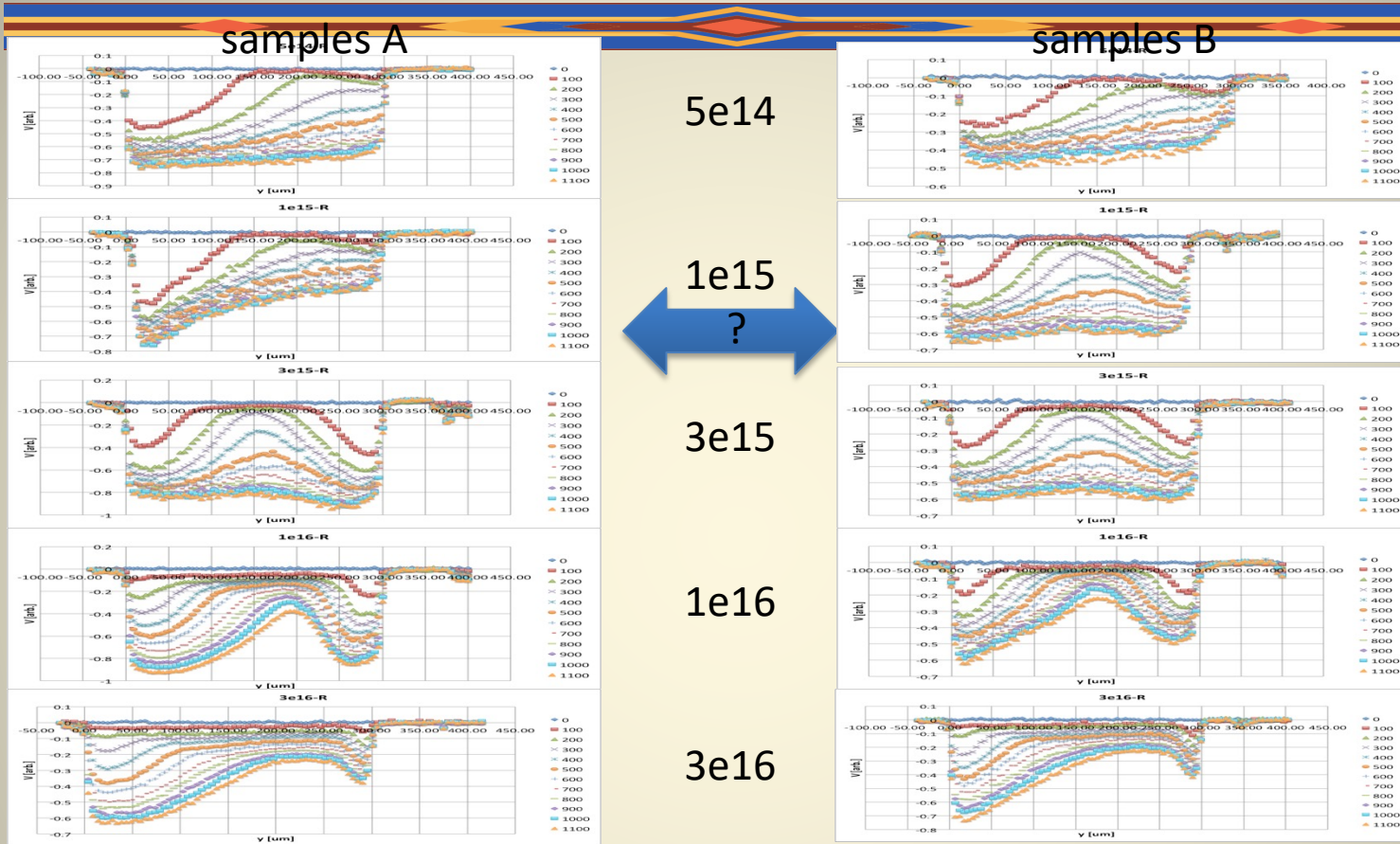
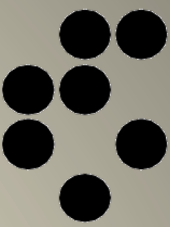
R.VAN OVERSTRAETEN and H.DE MAN, Solid-State Electronics 13(1970),583-608.
W.MAES, K.DE MEYER, R.VAN OVERSTRAETEN, Solid-State Electronics 33(1990),705-718.

$$\int_0^w dx \alpha_e(x) e^{-\int_0^x (\alpha_e(x') - \alpha_h(x')) dx'} = 1$$

Breakdown condition, can swap α_e with α_h



Reverse velocity profiles



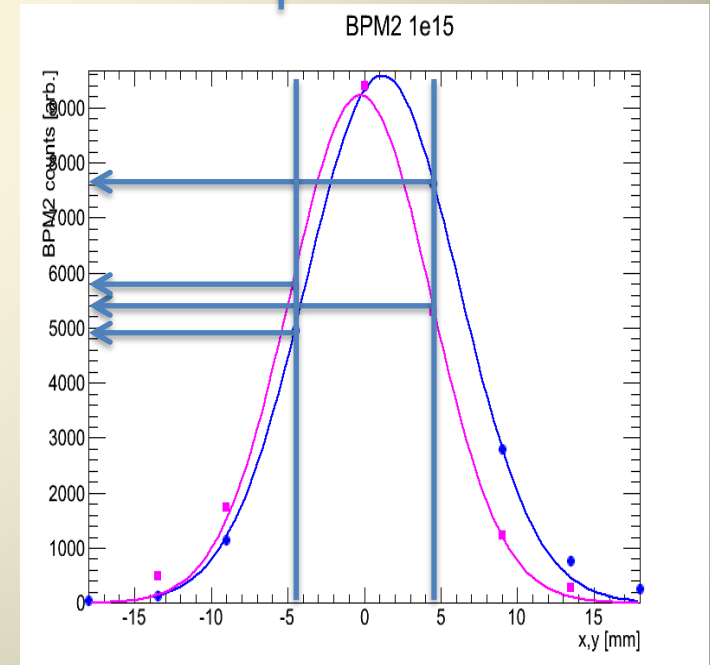
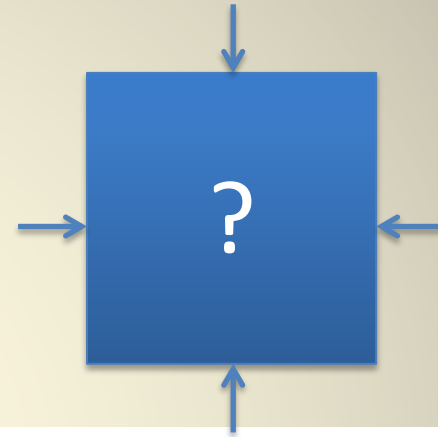
Something's fishy... never repeat experiments ?!



Explained by PS beam profile variation on sample edges

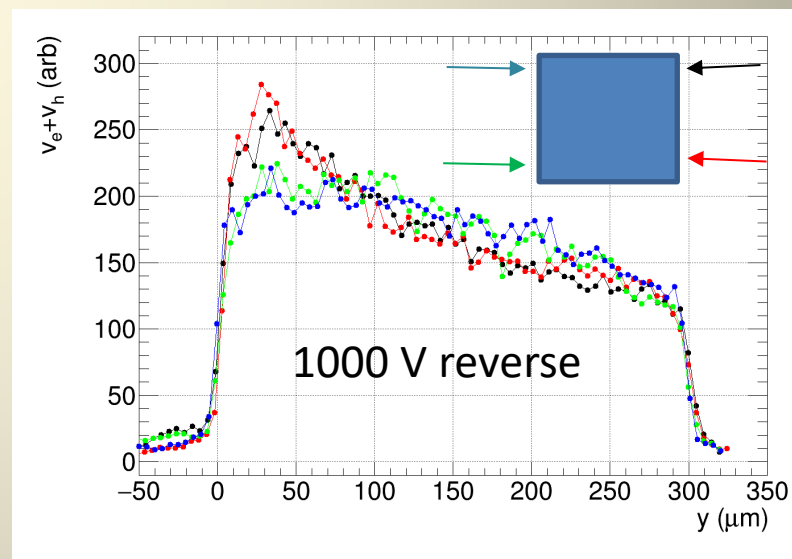
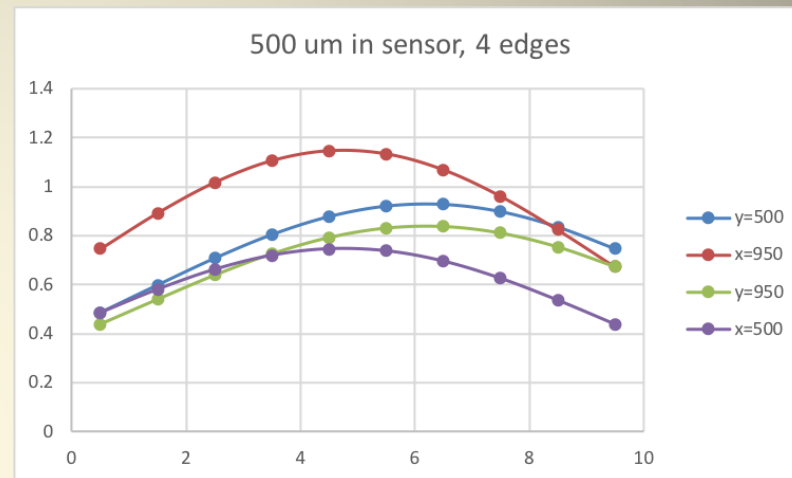
Proton irradiations - details

- Samples irradiated in PS in pairs
 - in series in same sample holder
- Same leakage current in both samples
 - ⇒ same *average* fluence received
- Beam profile asymmetric
 - monitored by BPM2
- Which side did we pick up ?



Protons revisited

- BPM2 results for the 1e15 sample, 0.5 mm in sensor
- 10x10 mm² average to peak: 0.7
 - Values rescaled
- Mid-side to average:
 - 1.17, 0.88, 0.82, 0.74
 - Must be the larger difference
 - Correct fluences by -10 %
 - Assign 20 % error
- Re-measured one sample from both sides, match with BPM2 data – still in progress
 - Looks like explaining the issue



Mobility Comparison



Table 3. Best-fitting parameters for the impurity dependence of electron and hole Ohmic mobilities at room temperature, as given in eqn (6)

	Electrons	Holes	Units
μ_{min}	92	47.7	$\text{cm}^2 \text{V}^{-1} \text{sec}^{-1}$
μ_{max}	1360	495	$\text{cm}^2 \text{V}^{-1} \text{sec}^{-1}$
N_{ref}	1.3×10^{17}	6.3×10^{16}	cm^{-3}
α	0.91	0.76	—

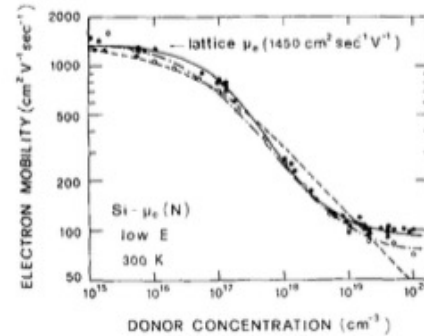


Fig. 5. Electron mobility, μ_n , in silicon at 300 K as a function of impurity concentration. Open and closed circles are the experimental results reported by Irvin[55] and of Mousty *et al.*[56], respectively. The continuous line is the phenomenological best fit (eqn (6)) of Baccarani and Ostioia[53] the broken line the best fit (eqn (7)) of Hilsun[54] the dot-dashed line (eqn (8)) of Scharfetter and Gummel[57] (see Tables 3 and 4).

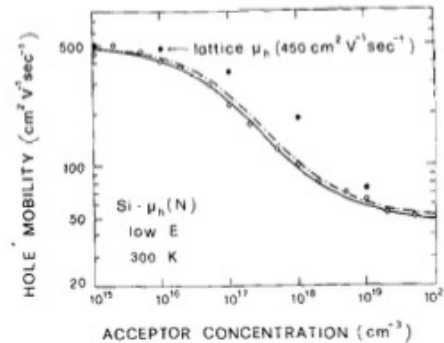


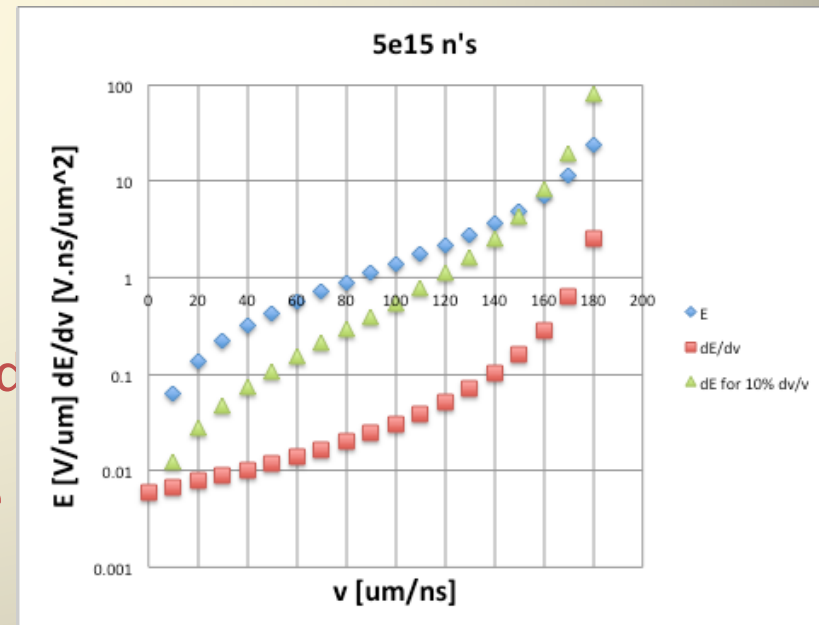
Fig. 6. Hole mobility, μ_p , in silicon at 300 K as a function of impurity concentration. Open circles are experimental results reported by Irvin[55]. Continuous and dot-dashed lines represent the best fitting curves of Caughey and Thomas[58] (eqn (6)) and of Scharfetter and Gummel[57] (eqn (8)), respectively (see Tables 3 and 4).

A REVIEW OF SOME CHARGE TRANSPORT PROPERTIES OF SILICON†
 C. JACOBONI, C. CANALI, G. OTTAVIANI AND A. ALBERICI QUARANTA
 Istituto di Fisicadell'Universitadi Modena, 41100 Modena, Italy
 (Received 18 March 1976; in revised form 12 July 1976)

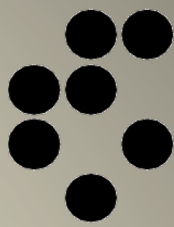
- Dependence on *shallow* dopant concentration
 - Measured in the roaring 60's
- Characteristic trap concentration $N \sim 10^{17} \text{ cm}^{-3}$
 - looks out of reach for typical $g=0(10^{-2})$
- But g refers to $N_{eff} = |N_a - N_d|$
- While N is more like $N_a + N_d$
 - *x-sections for deep and shallow?*
- Power law looks compatible: $\alpha \leq 1$

Velocity and Field Profiles

- Knowing $v(E)$ can set scale to velocity profiles
 - assumption: same scale on FW and reverse bias
 - protons: for 5×10^{14} and 10^{15} use same scale, fixed by average field for 5×10^{14} at 1100 V (no good FW data)
- Invert $E(v)$ to get electric field profiles
 - big errors when approaching v_{sat} i.e. at high E
 - exaggerated by CM in high field regions
 - $v > v_{sat}$ not physical, but can be faked by CM

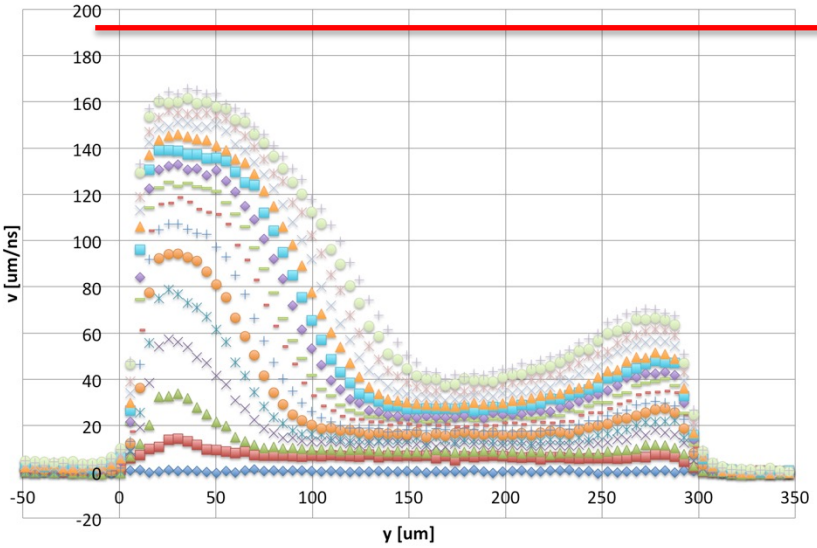


Velocity Profiles Neutrons



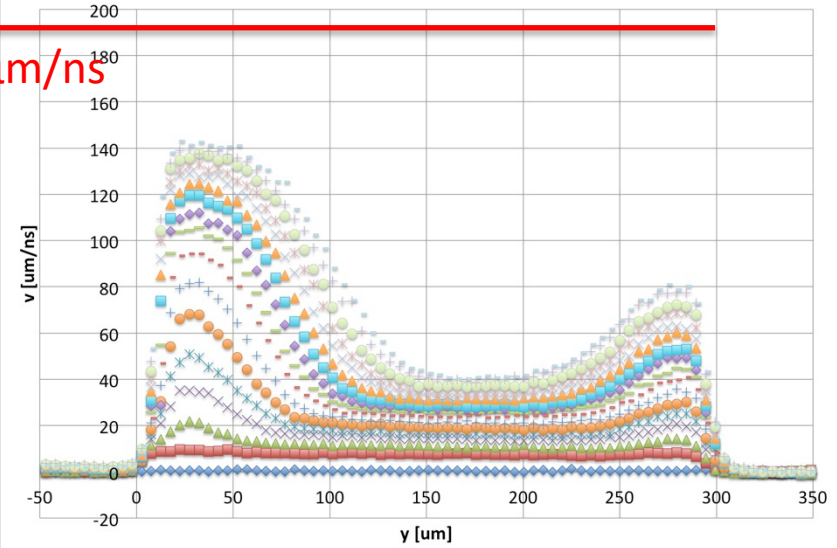
Velocity profile 5e15

Velocity profile 1e16



$v = 190 \mu\text{m/ns}$

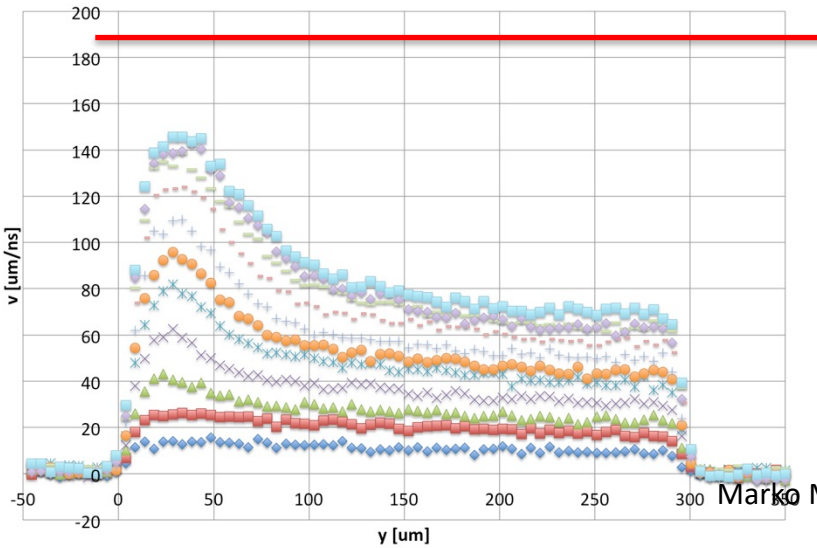
- 0
- 100
- 150
- 200
- 250
- 300
- 350
- 400
- 450
- 500
- 550
- 600
- 650
- 700
- 750



- 0
- 50
- 100
- 150
- 200
- 250
- 300
- 350
- 400
- 450
- 500
- 550
- 600
- 650
- 700
- 750
- 800

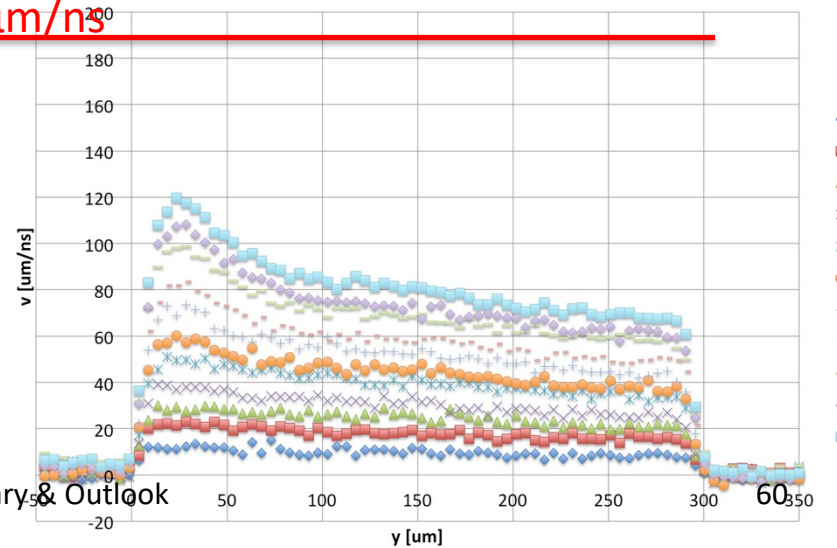
Velocity profile 5e16

Velocity profile 1e17



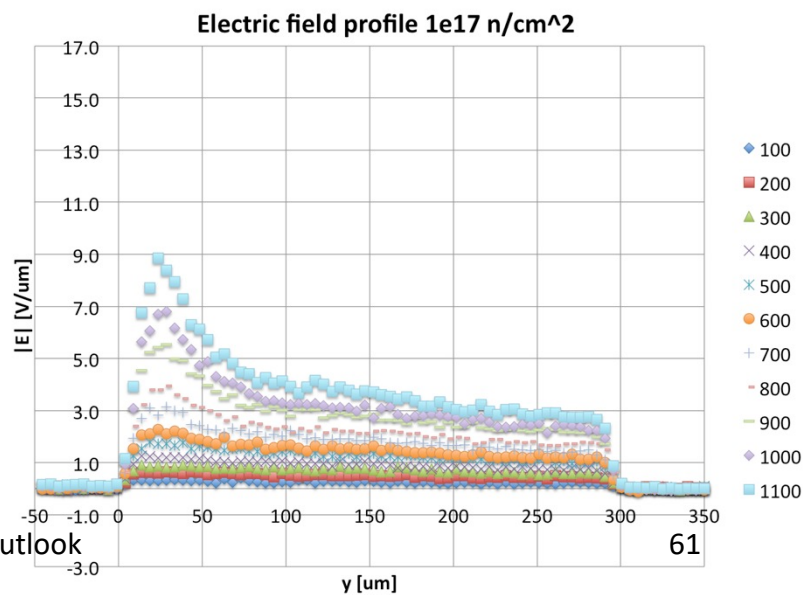
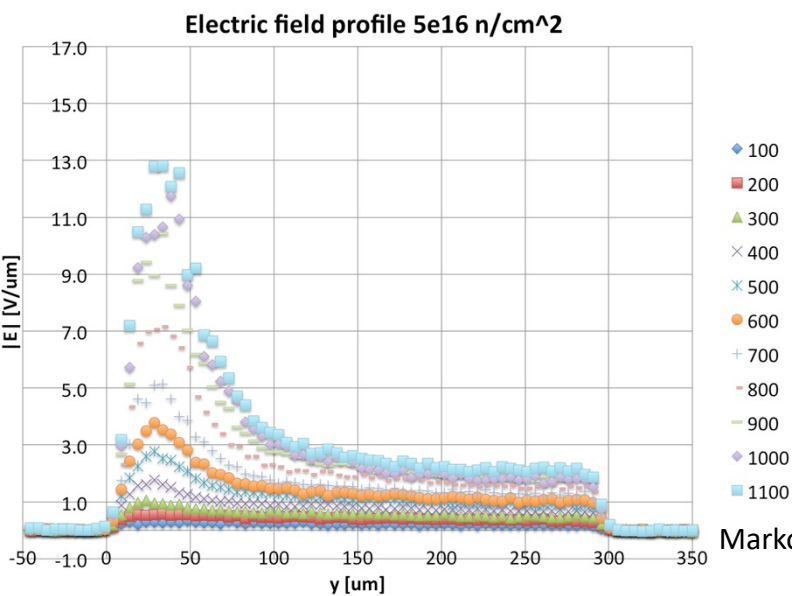
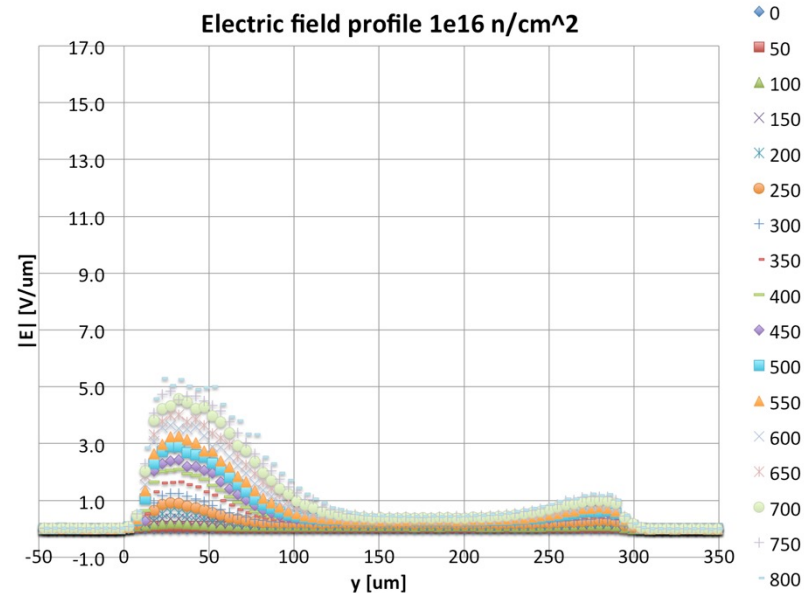
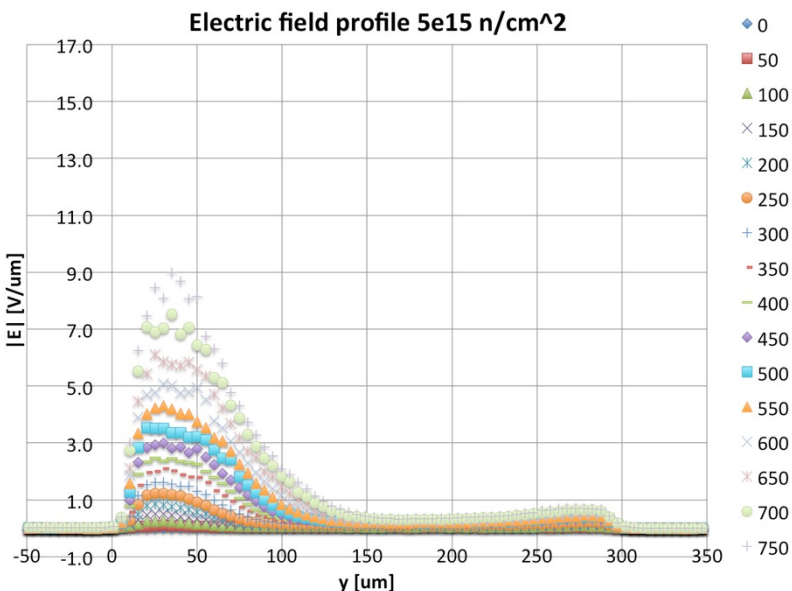
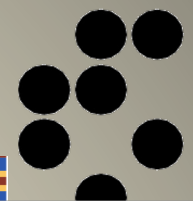
$v = 190 \mu\text{m/ns}$

- 100
- 200
- 300
- 400
- 500
- 600
- 700
- 800
- 900
- 1000
- 1100

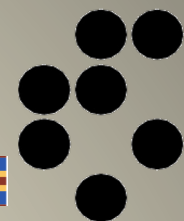


- 100
- 200
- 300
- 400
- 500
- 600
- 700
- 800
- 900
- 1000
- 1100

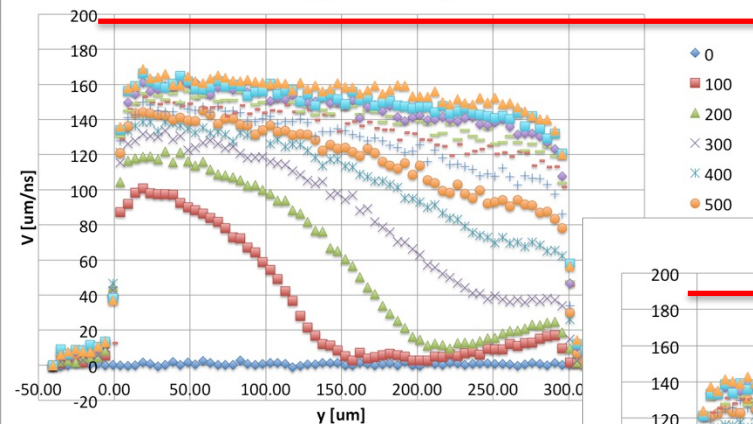
Field Profiles Neutrons



Velocity Profiles Protons

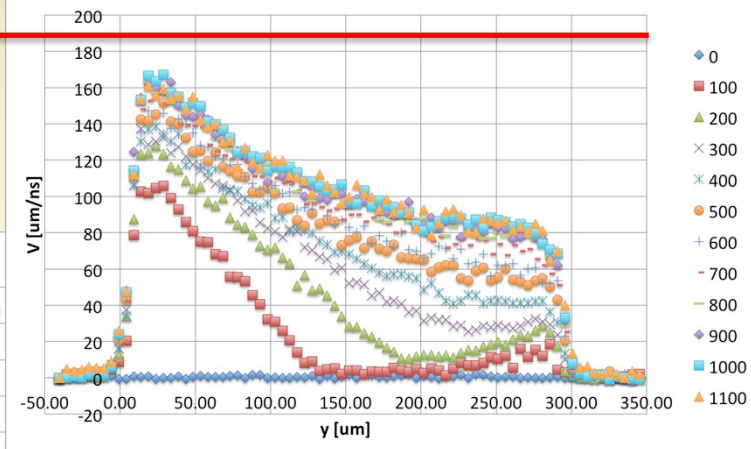


Velocity profile 5e14 p/cm²

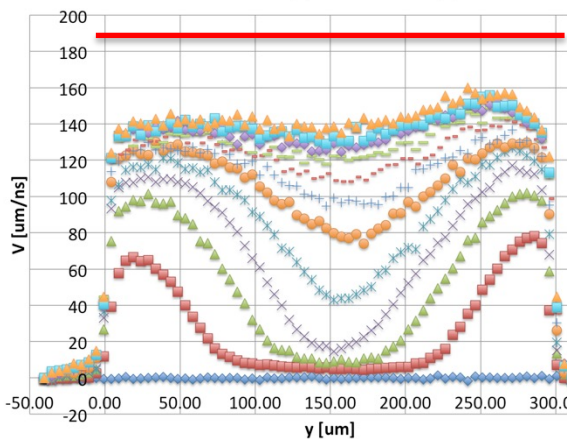


$v = 190 \mu\text{m/ns}$

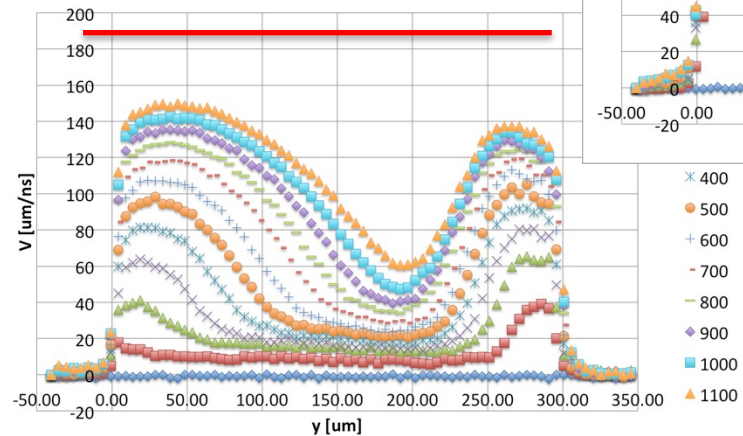
Velocity profile 1e15 p/cm²



Velocity profile 2.9e15 p/cm²

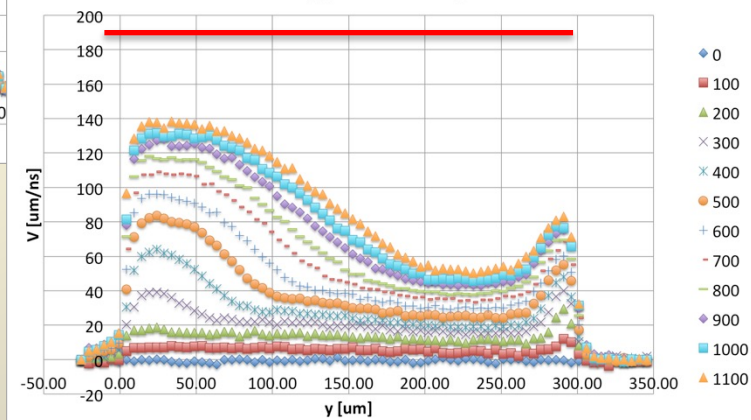


Velocity profile 1.1e16 p/cm²

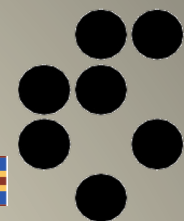


Same scale as
for neutrons

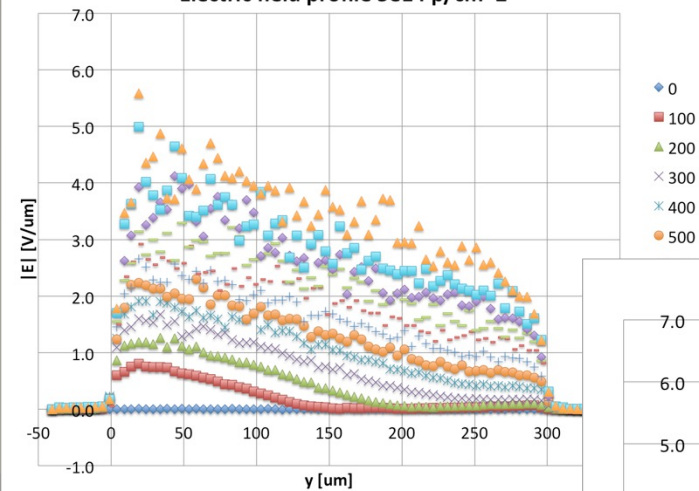
Velocity profile 2.8e16 p/cm²



Field Profiles Protons

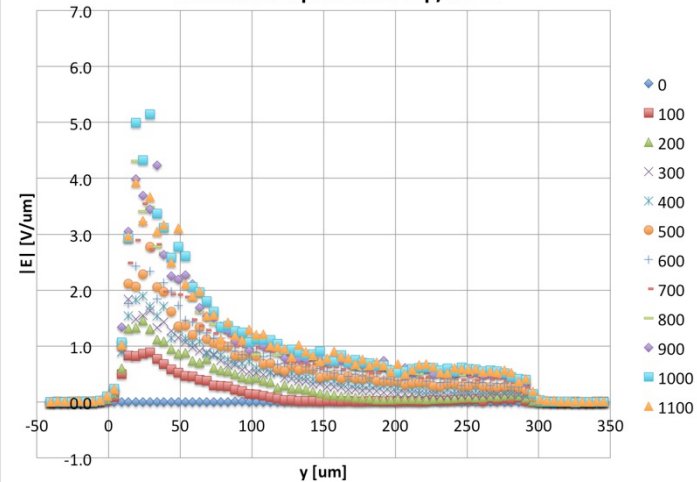


Electric field profile $5e14 \text{ p/cm}^2$

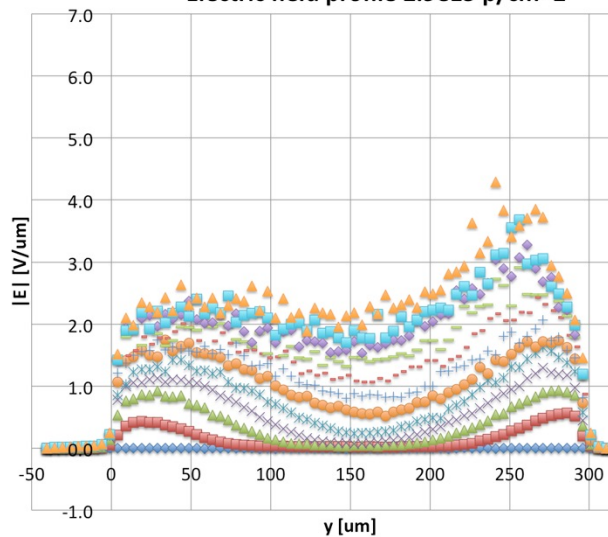


Smaller peak fields
than for neutrons
Scale 0-7 V/ μm

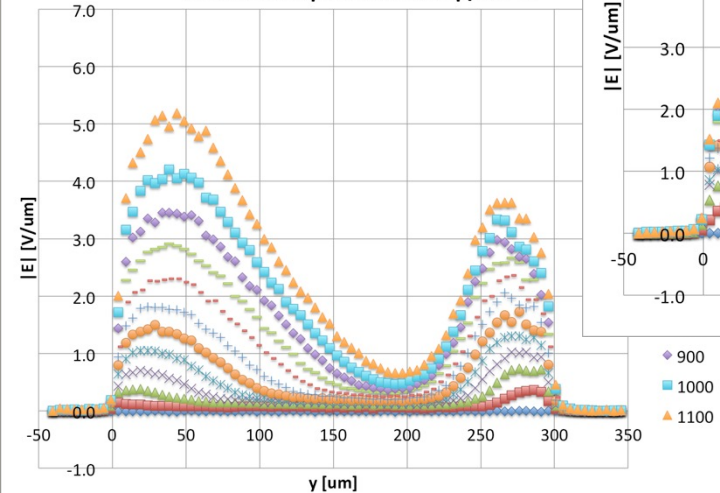
Electric field profile $1e15 \text{ p/cm}^2$



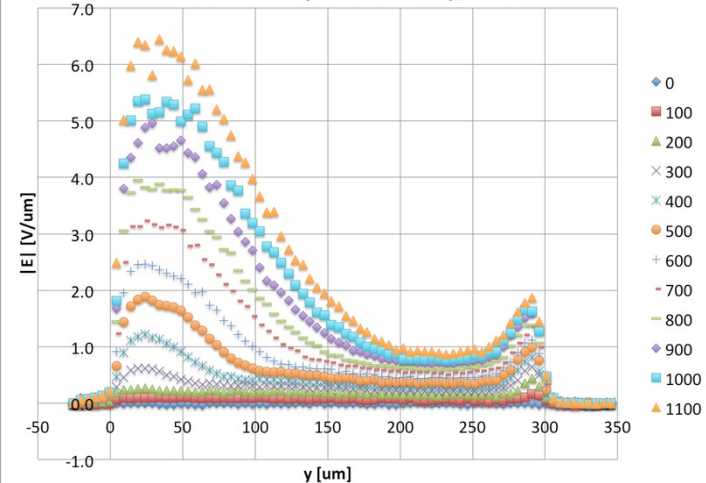
Electric field profile $2.9e15 \text{ p/cm}^2$



Electric field profile $1.1e16 \text{ p/cm}^2$

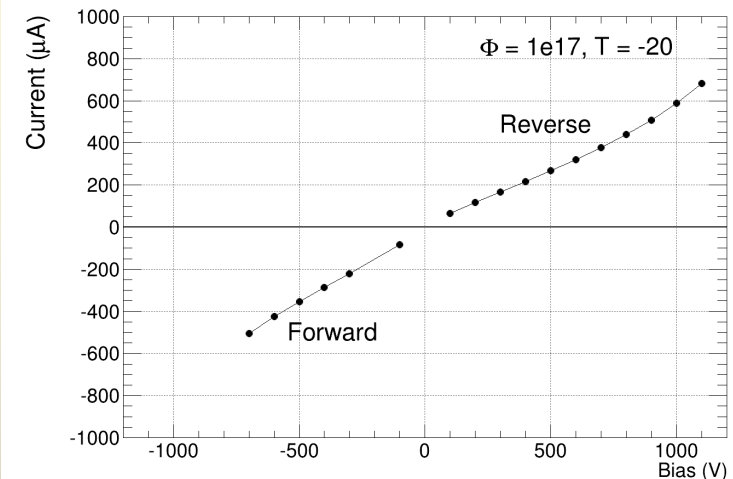
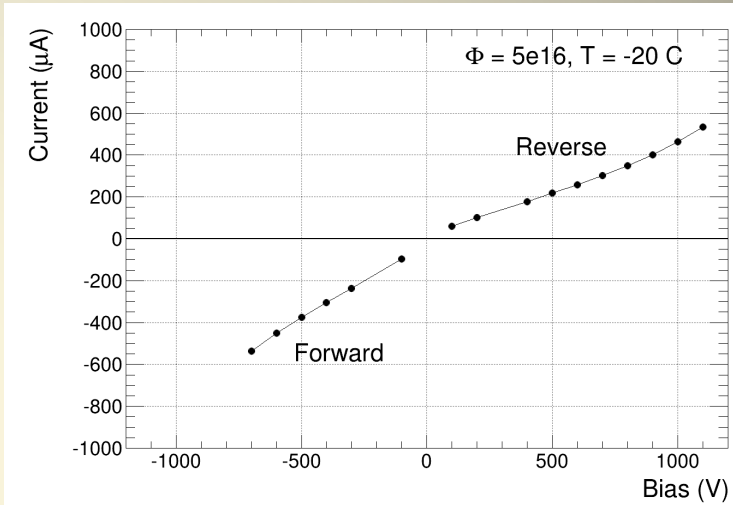


Electric field profile $2.8e16 \text{ p/cm}^2$

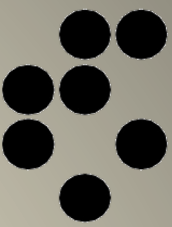


Current Characteristics

- Smooth behaviour in both directions
 - Highly resistive Si limits FW injection
- Reverse current smaller than predicted by an order of magnitude
- Both currents rising \sim linear with bias
 - Slopes FW/reverse more compatible at higher fluences
- Consistent with recent measurements at highest fluences



Trapping Considerations



- Extrapolation from low fluence data with $\beta_{e,h}(-20^\circ\text{C})=4.4, 5.8 \times 10^{-16} \text{ cm}^2/\text{ns}$; $1/\tau = \beta \Phi$

Φ [1e15]	5	10	50	100
τ [ps]	400	200	40	20
$mfp@v_{sat}$ [μm]	95	48	9.5	4.8
MPV [e_0]	7600	3800	760	380
MPV@1000 V	8900	5500	1800	1150
CCD _{1000 V} [μm]	110	70	23	14

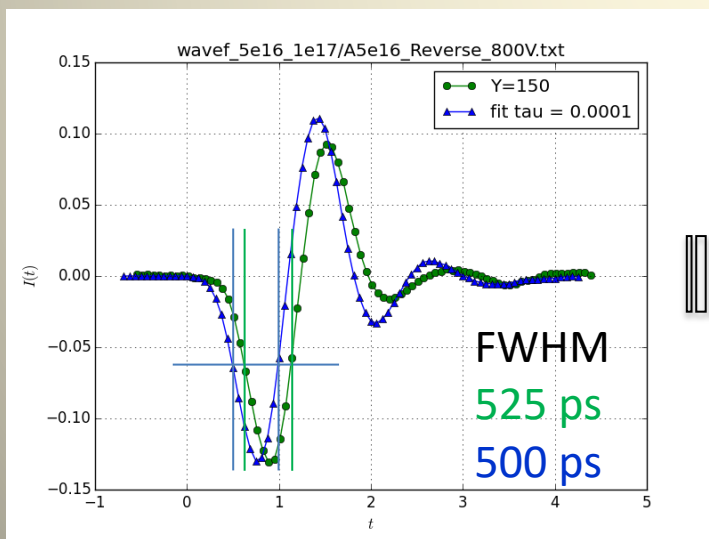
From "magic formula"
JINST 9 P10016(2014)



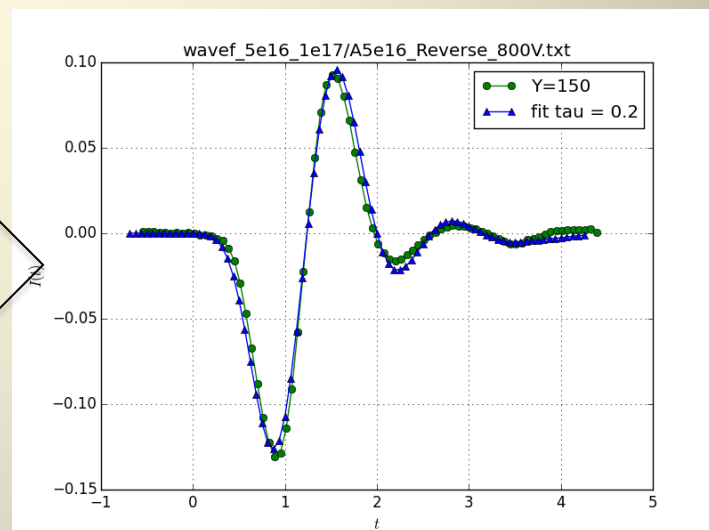
- Measured data exceeds (by far) linear extrapolation of trapping
 - n.b.1: $E \sim 3 \text{ V}/\mu\text{m}$ by far not enough to saturate velocity
 - n.b.2: little sign of CM at highest fluences

Exploiting TCT Waveforms

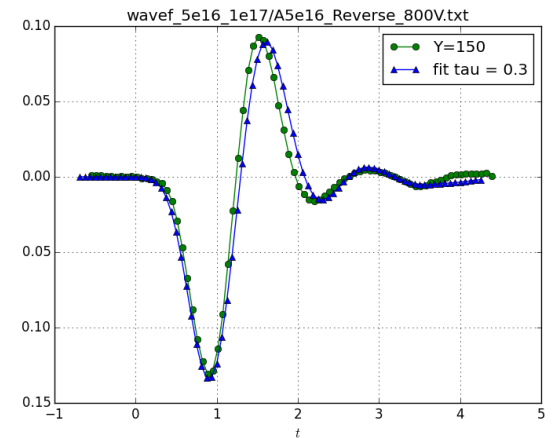
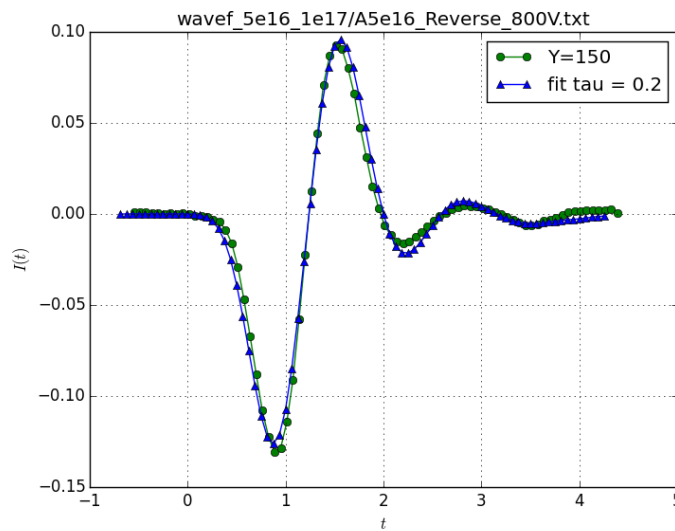
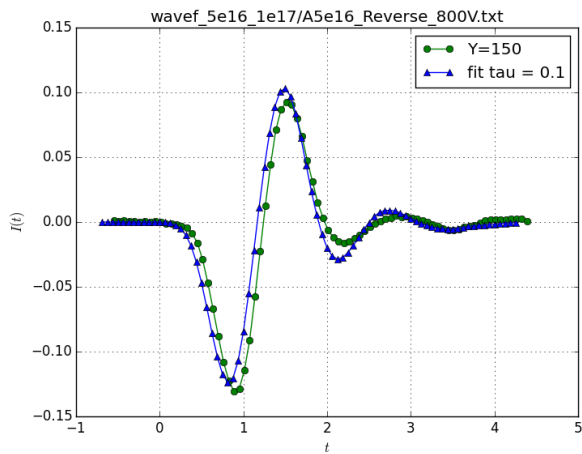
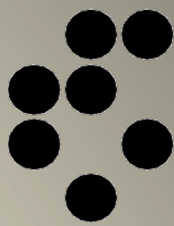
- Waveforms at $y=100 \mu\text{m}$, 800 V, 5×10^{16} and 10^{17}
 - $E \approx 3 \text{ V}/\mu\text{m}$, CCD/2 implies signal within $\sim 10 \mu\text{m}$ or $< 0.2 \text{ ns}$
 - the rest you see is the transfer function of the system
- Still distinct signals from the two fluences
 - treat 10^{17} waveform as transfer function of the system
 - convolute with $e^{-t/\tau}$ to match 5×10^{16} response
 - $\tau = 0.2 \text{ ns}$ provides a good match
- In fact, measure $\sim \Delta\tau$, as “transfer” already convoluted with $e^{-t/\tau(1e17)}$!



$\tau = 0.2 \text{ ns}$



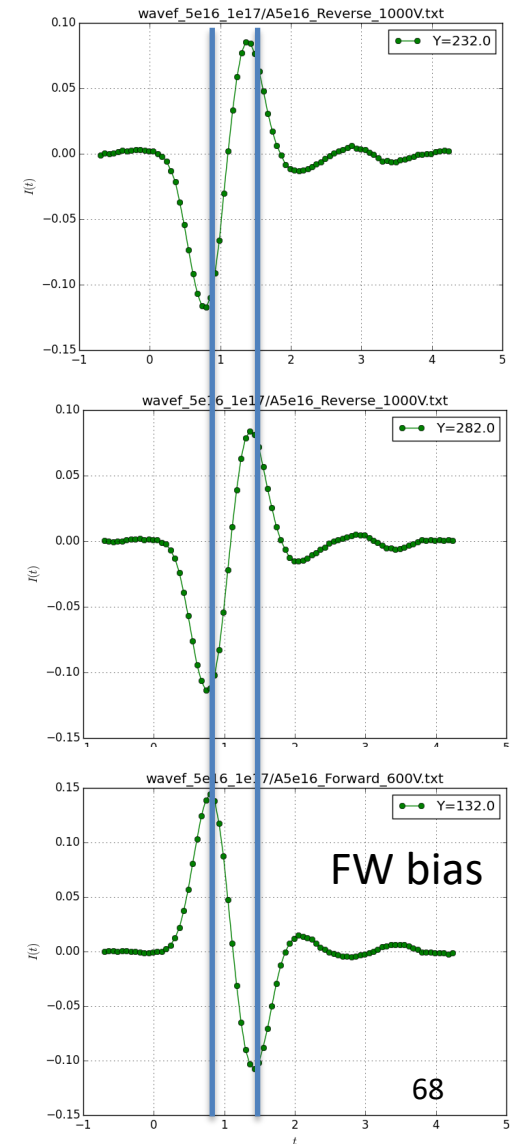
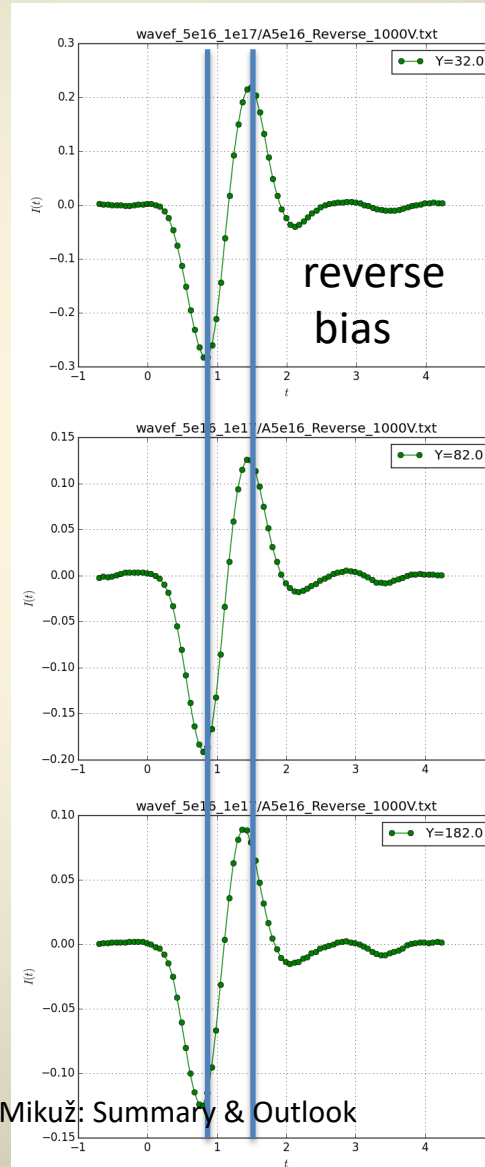
Waveforms: How sensitive ?



- $\Delta\tau = 0.2$ ns certainly best fit, 0.1 too narrow, 0.3 too broad
- precision ~ 50 ps

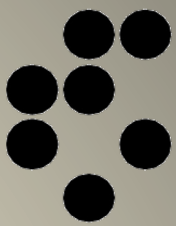
Trapping – position dependence ?

- Waveforms plotted every 50 μm in detector depth for reverse bias at 1000 V
- Forward bias in middle of detector added at 600 V
- Very little, if any, wf dependence on position observed
- Trapping not position dependent !?





Trapping @3e17



- Moved to another setup – different waveforms
 - Widths of reverse and FW similar
 - With decreases 1- \rightarrow 3e17
 - Irregular waveforms with small signal @3e17
 - Hard to state something more quantitative

